

REDUCING REFRESH POWER IN MOBILE DEVICES WITH MORPHABLE ECC

DSN-45

06/24/2015

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GROWING DRAM SIZE IN SMARTPHONES

Smartphone usability: battery life



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30% energy goes to memory system in idle mode



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Samsung Galaxy S2 (2011)
1GB DRAM



Samsung Galaxy S6 (2015)
3GB DRAM

GROWING DRAM SIZE IN SMARTPHONES

Smartphone usability: battery life

30% energy goes to memory system in idle mode



Samsung Galaxy S2 (2011)
1GB DRAM

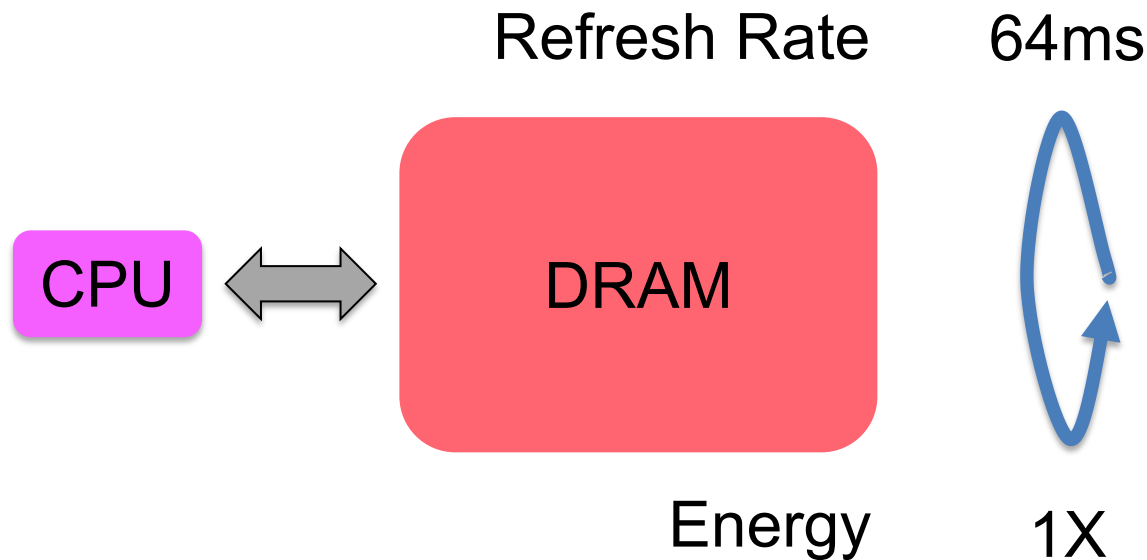


Samsung Galaxy S6 (2015)
3GB DRAM

DRAM Refresh accounts for significant energy consumption in idle mode

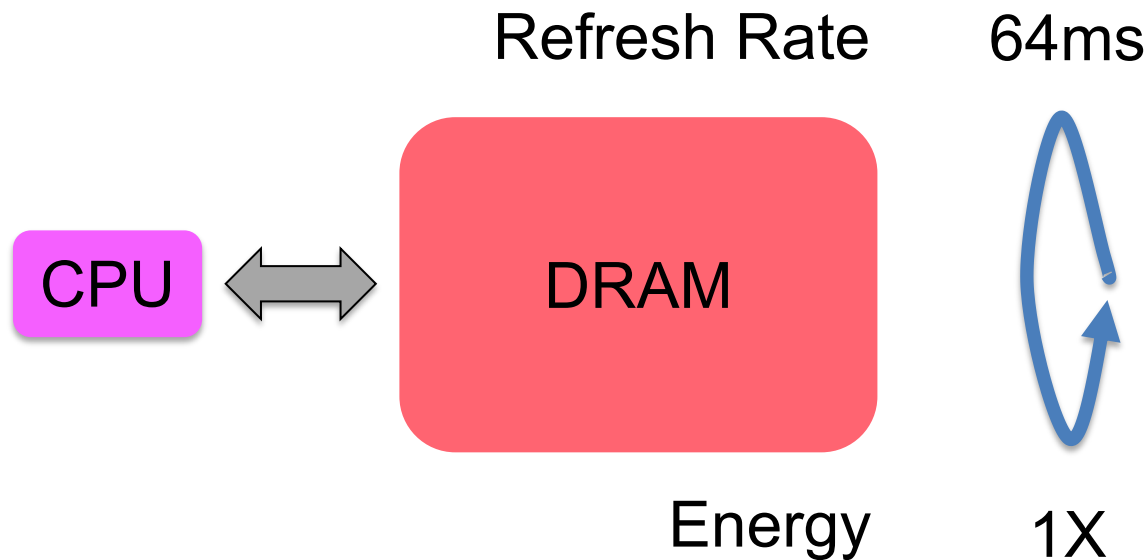
LOWER REFRESH RATE FOR ENERGY

Current standard refresh rate: 64ms



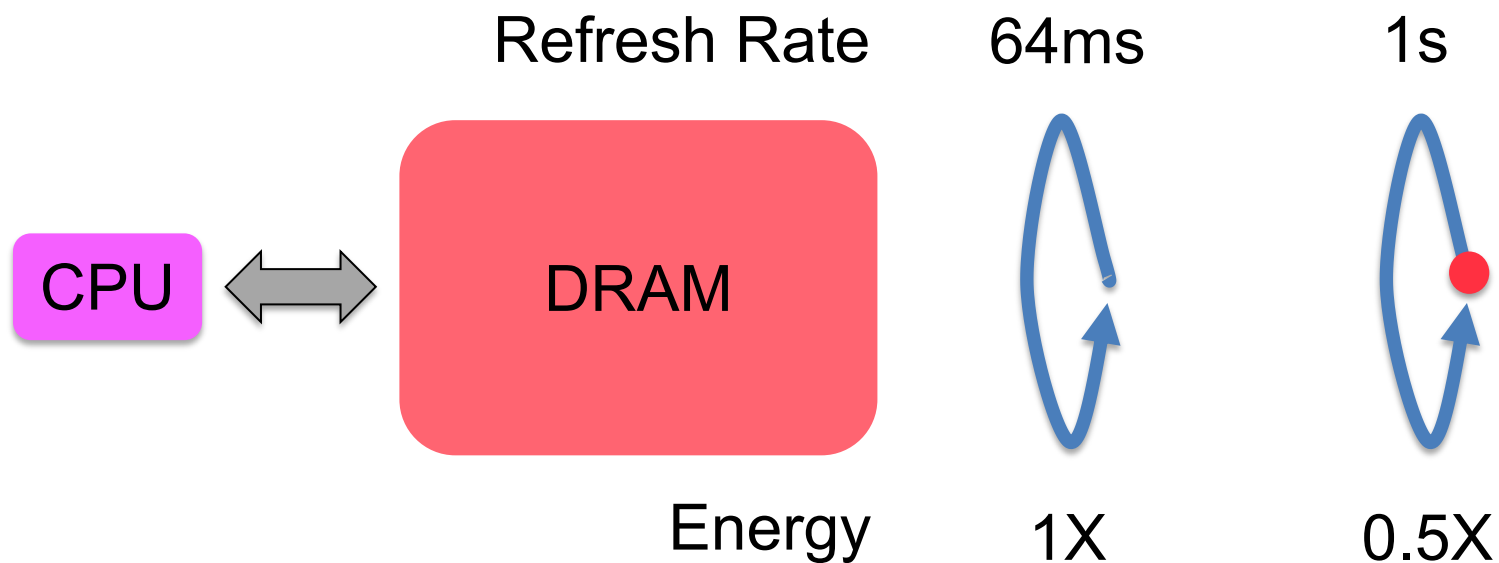
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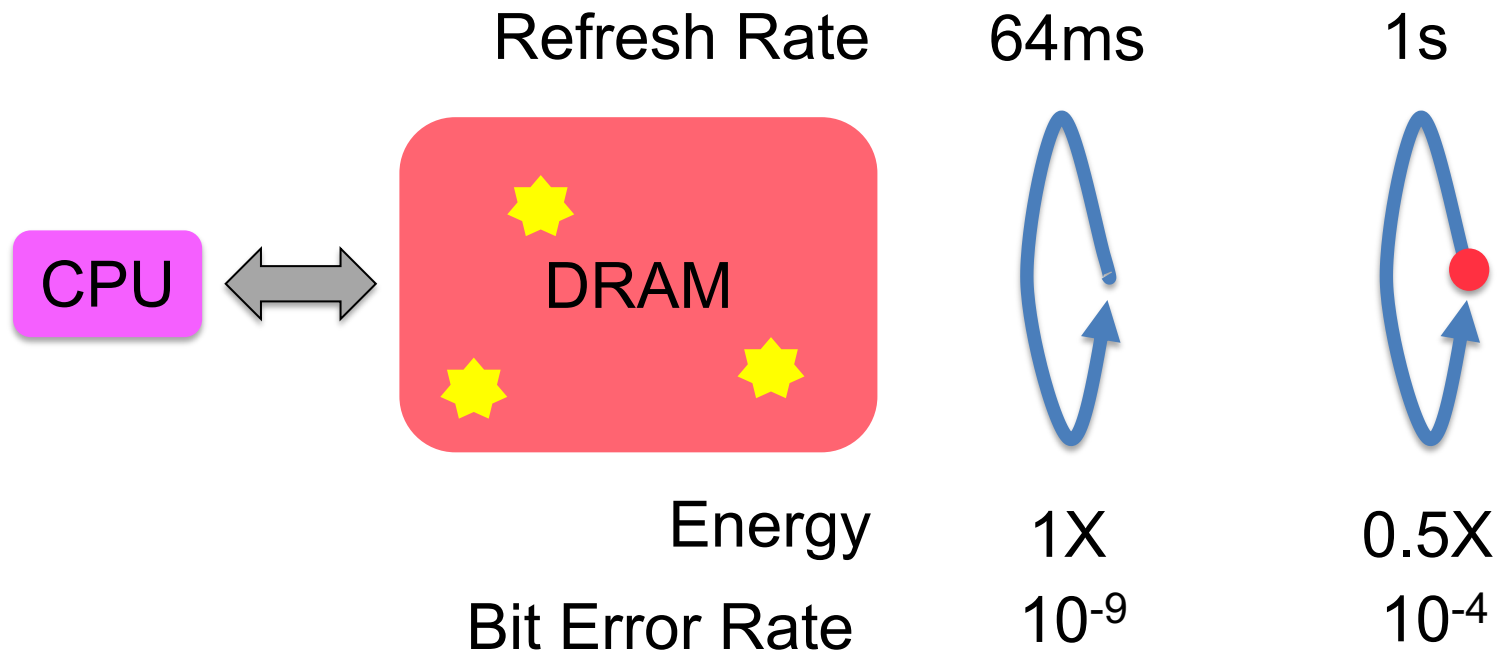
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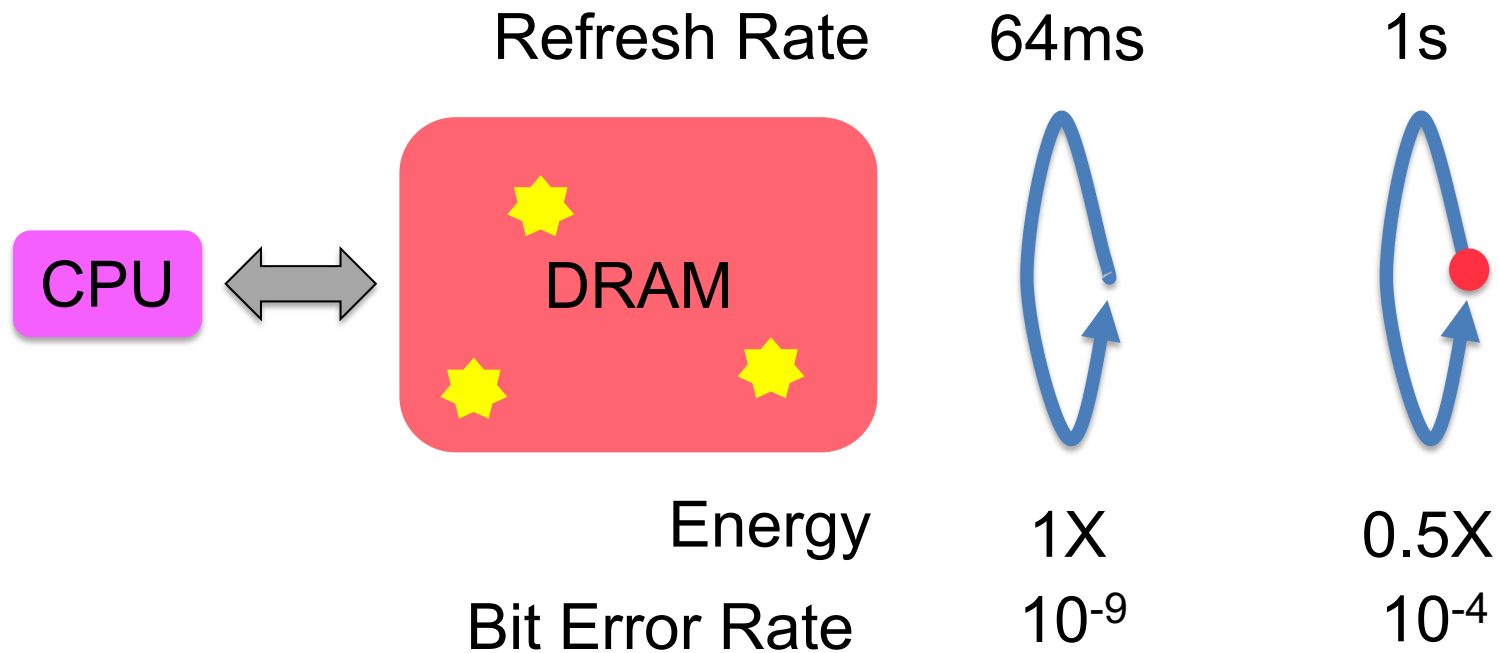
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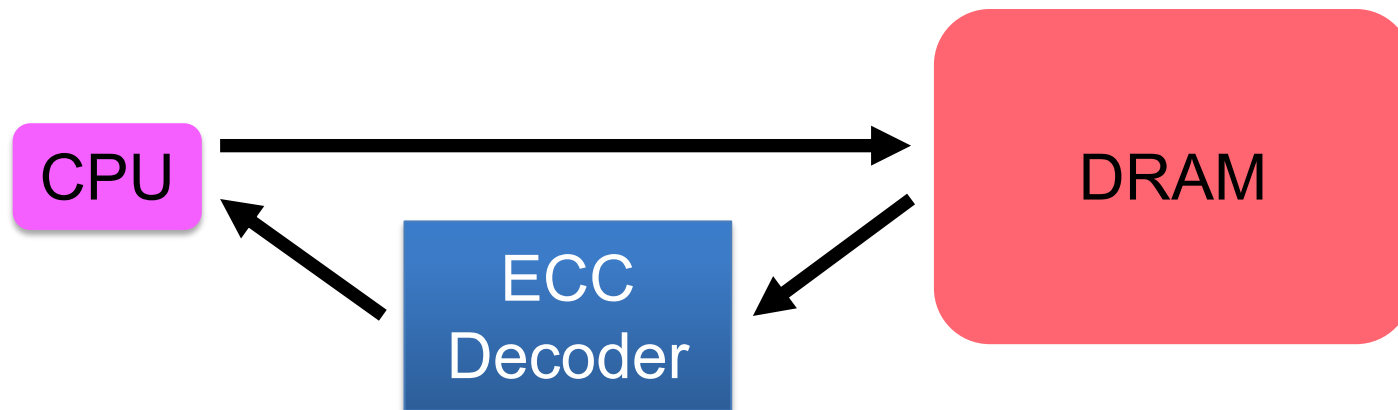
Current standard refresh rate: 64ms



Use ECC to protect DRAM from refresh errors

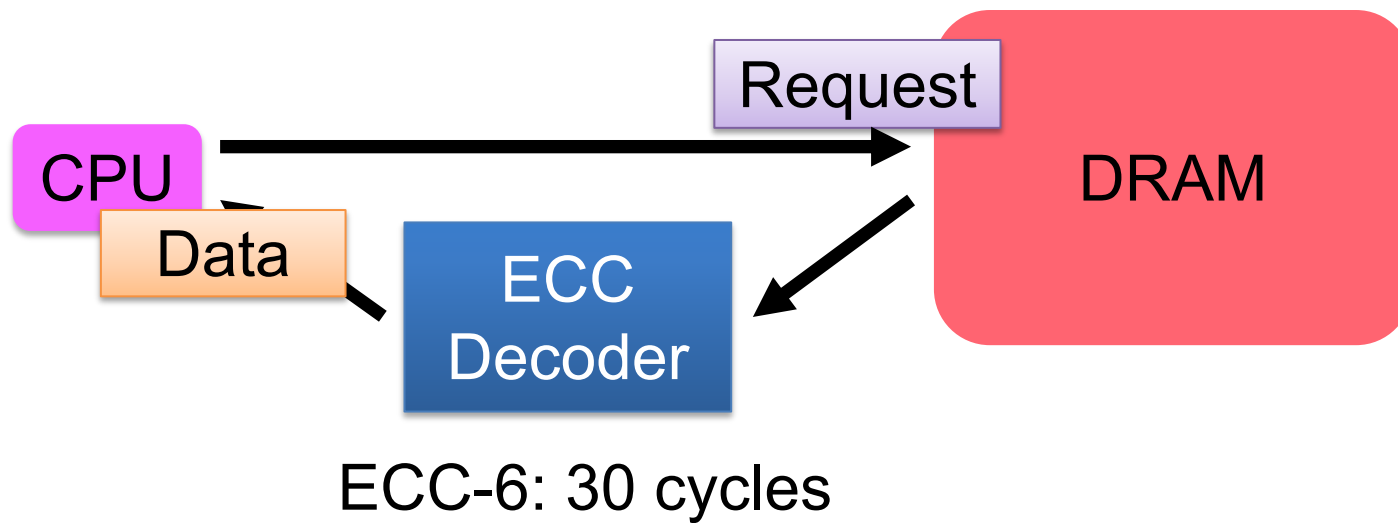
ECC-6 INCURS LONG LATENCY FOR READ

Decoder latency is on the critical path



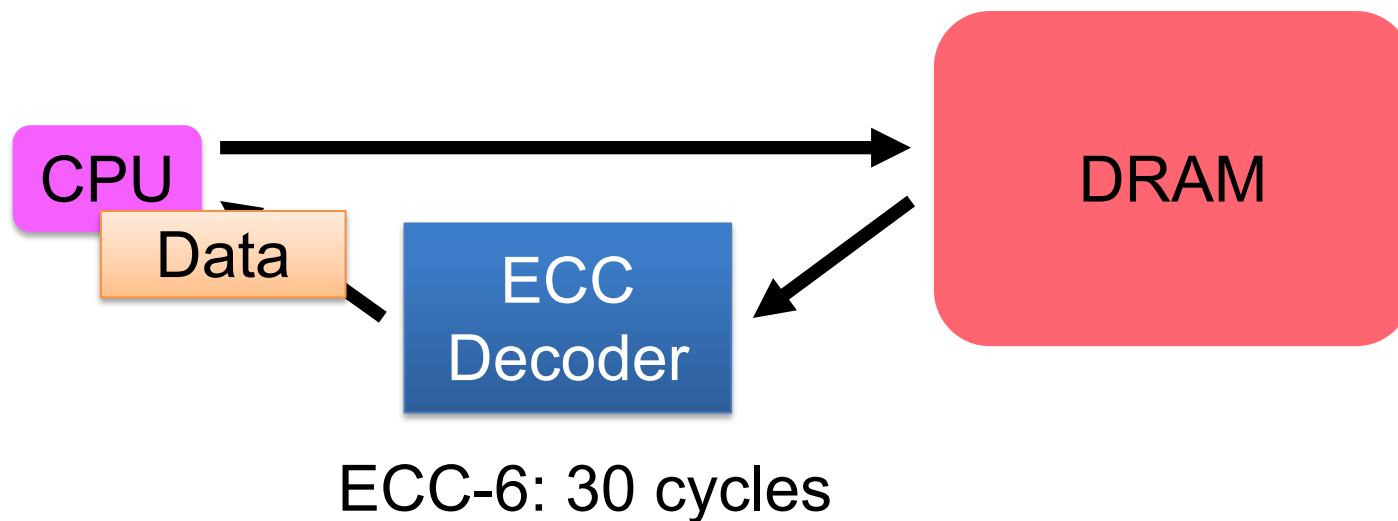
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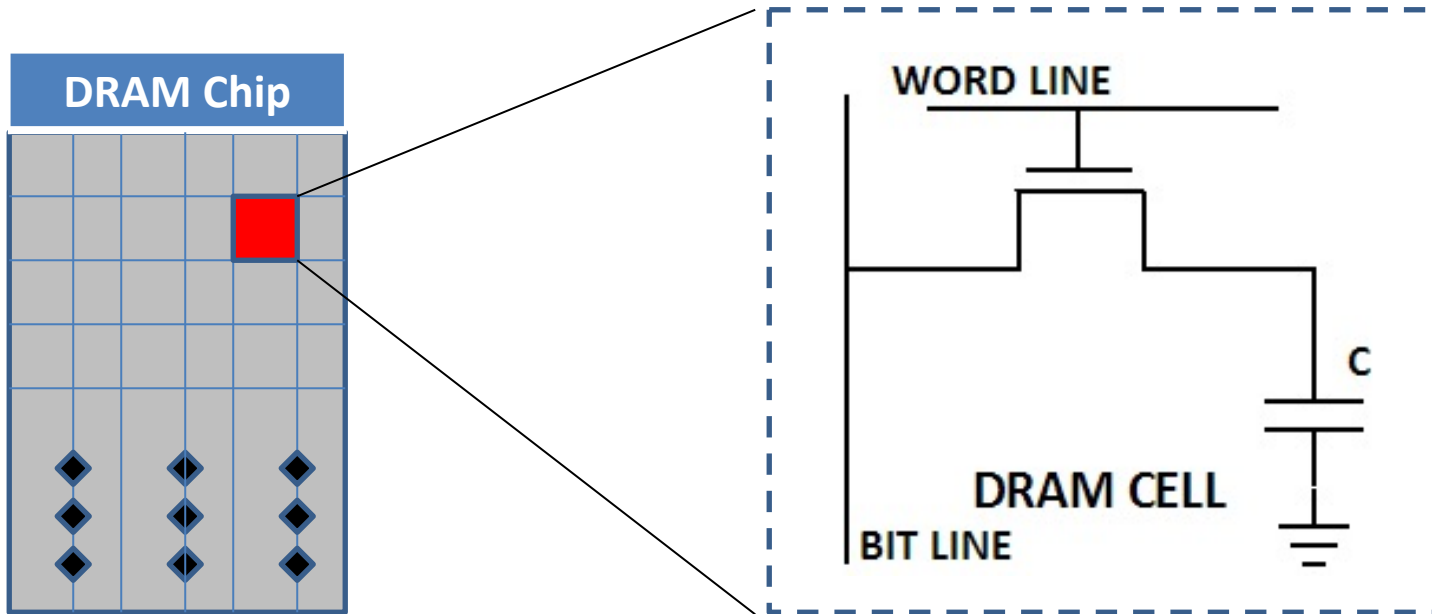
**We want energy reduction in idle mode,
and maintain performance in active mode**

AGENDA

- Introduction
- **Background**
 - DRAM 101
 - Refresh and Errors
 - Error Correction Codes (ECC)
- Morphable ECC
- Results
- Summary

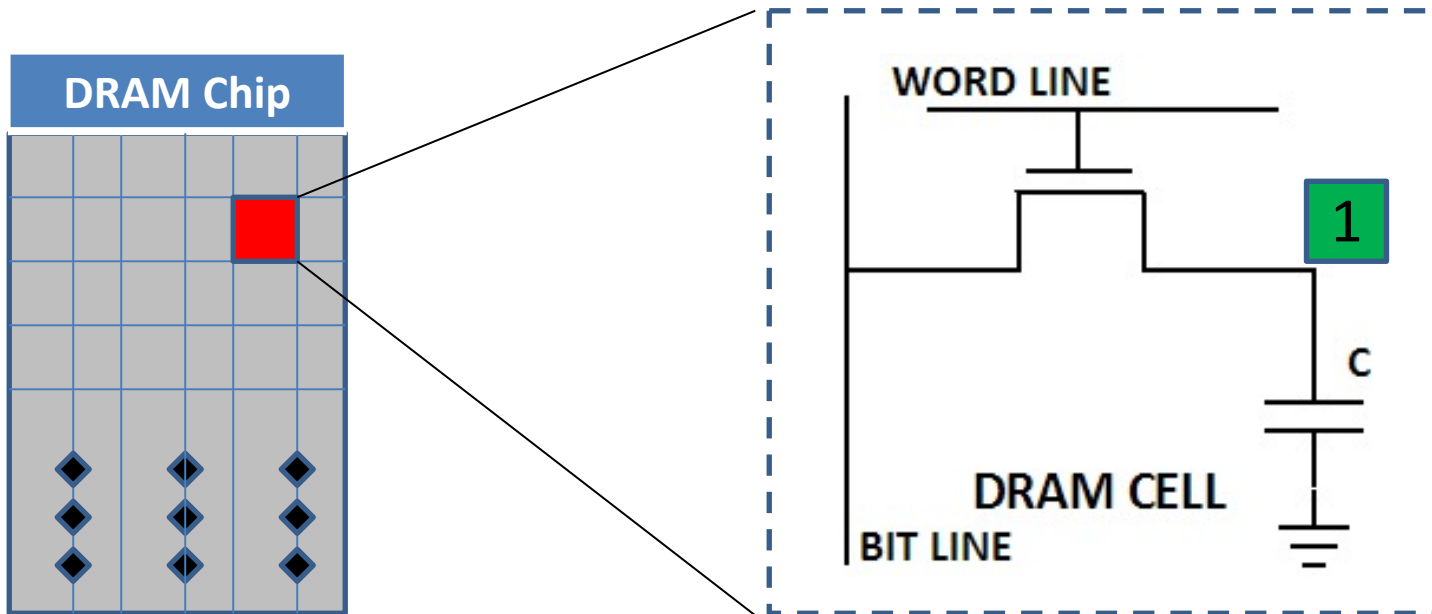
DRAM 101

- Dynamic Random Access Memory (DRAM)
- DRAM stores data as charge on capacitor



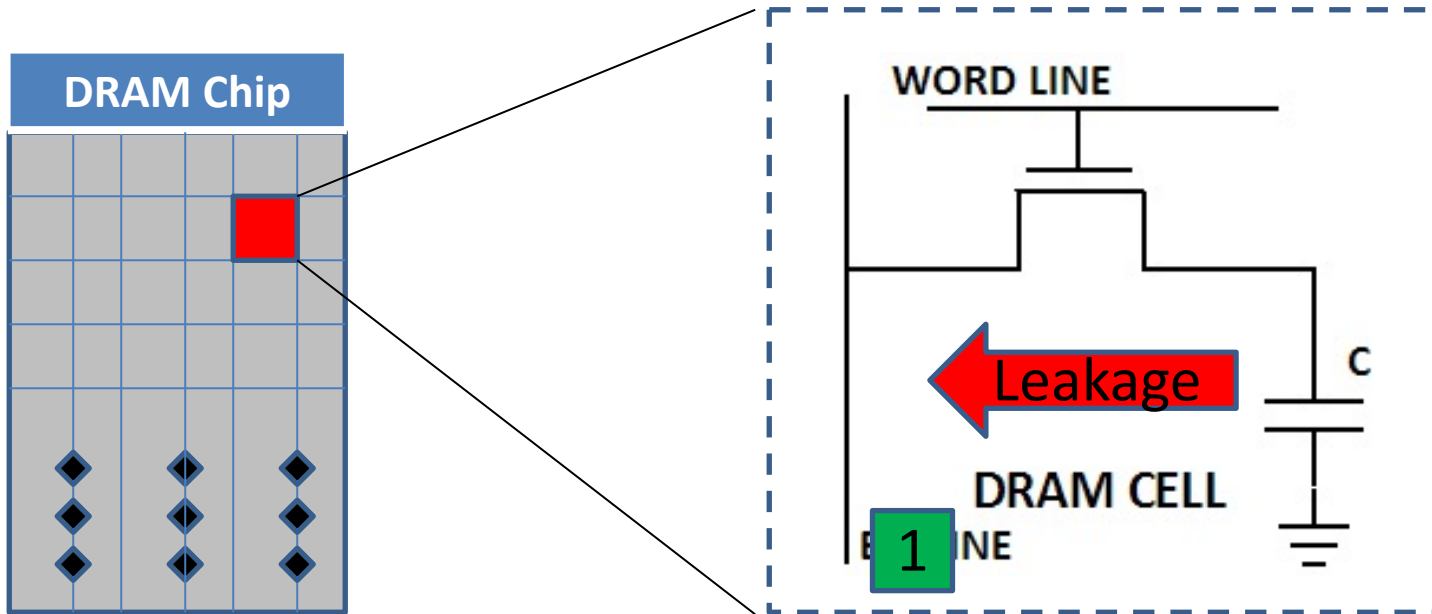
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DRAM 101

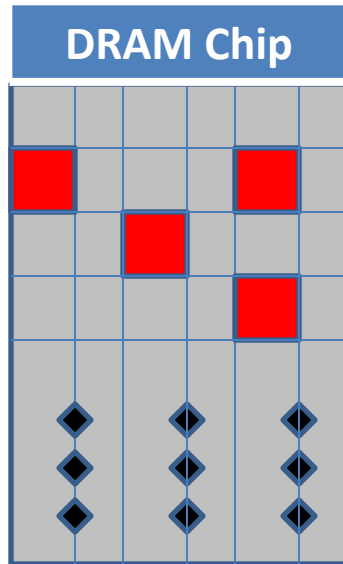
- Dynamic Random Access Memory (DRAM)
- DRAM stores data as charge on capacitor



DRAM is a volatile memory → charges leak quickly

DRAM REFRESH

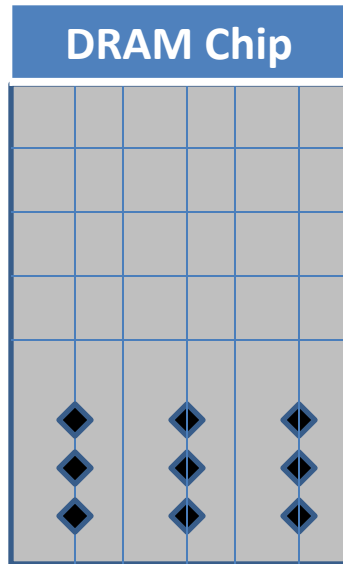
DRAM maintains data integrity by Refresh operations



JEDEC: 64ms

DRAM REFRESH

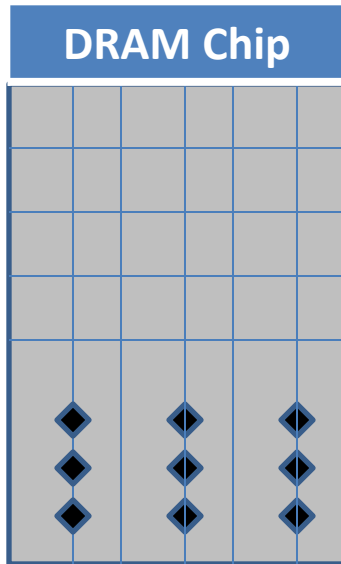
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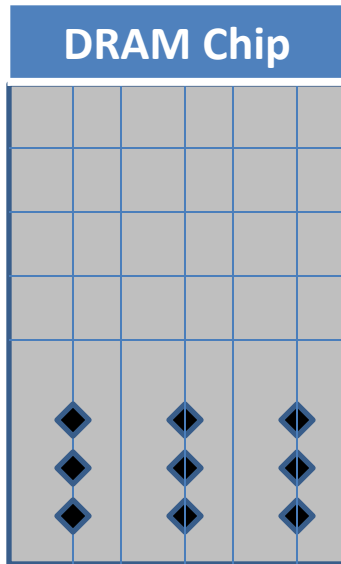
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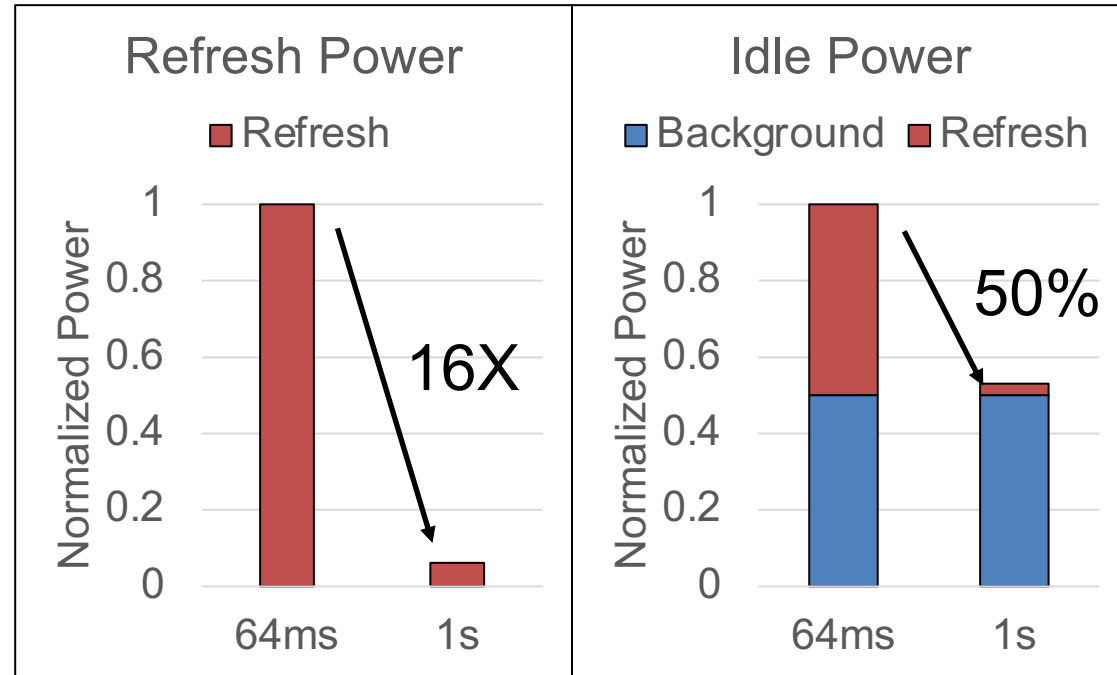
JEDEC: 64ms \rightarrow 1s

DRAM REFRESH

DRAM maintains data integrity by Refresh operations



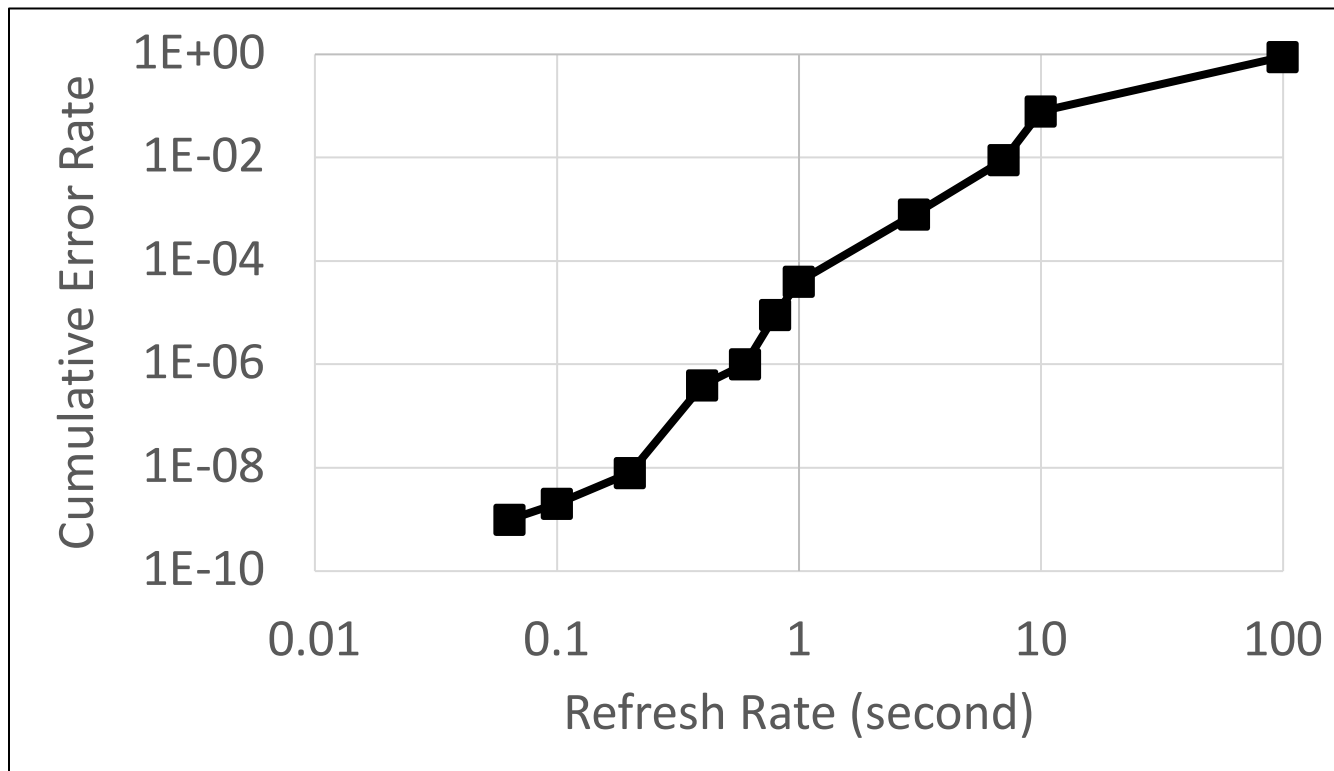
JEDEC: 64ms → 1s



Lowering refresh rate reduces power

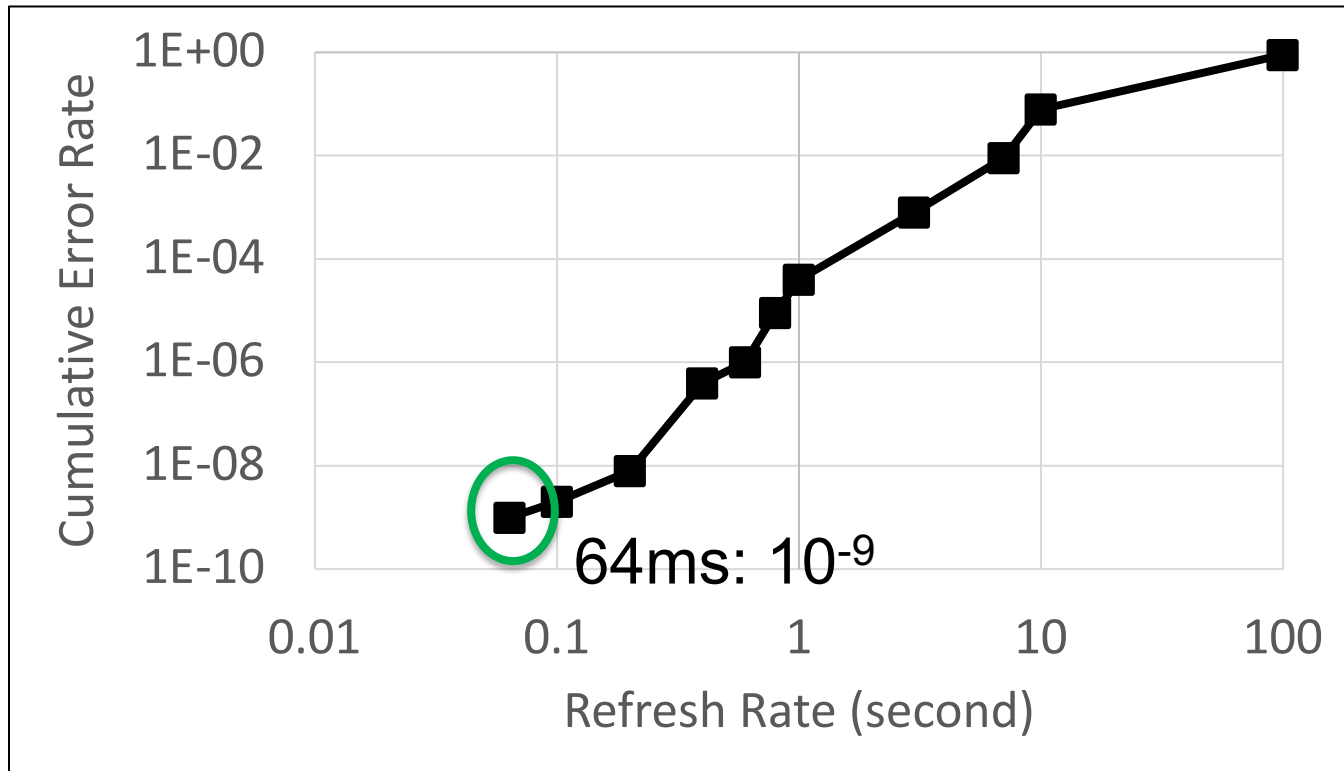
DRAM REFRESH RATE AND ERRORS

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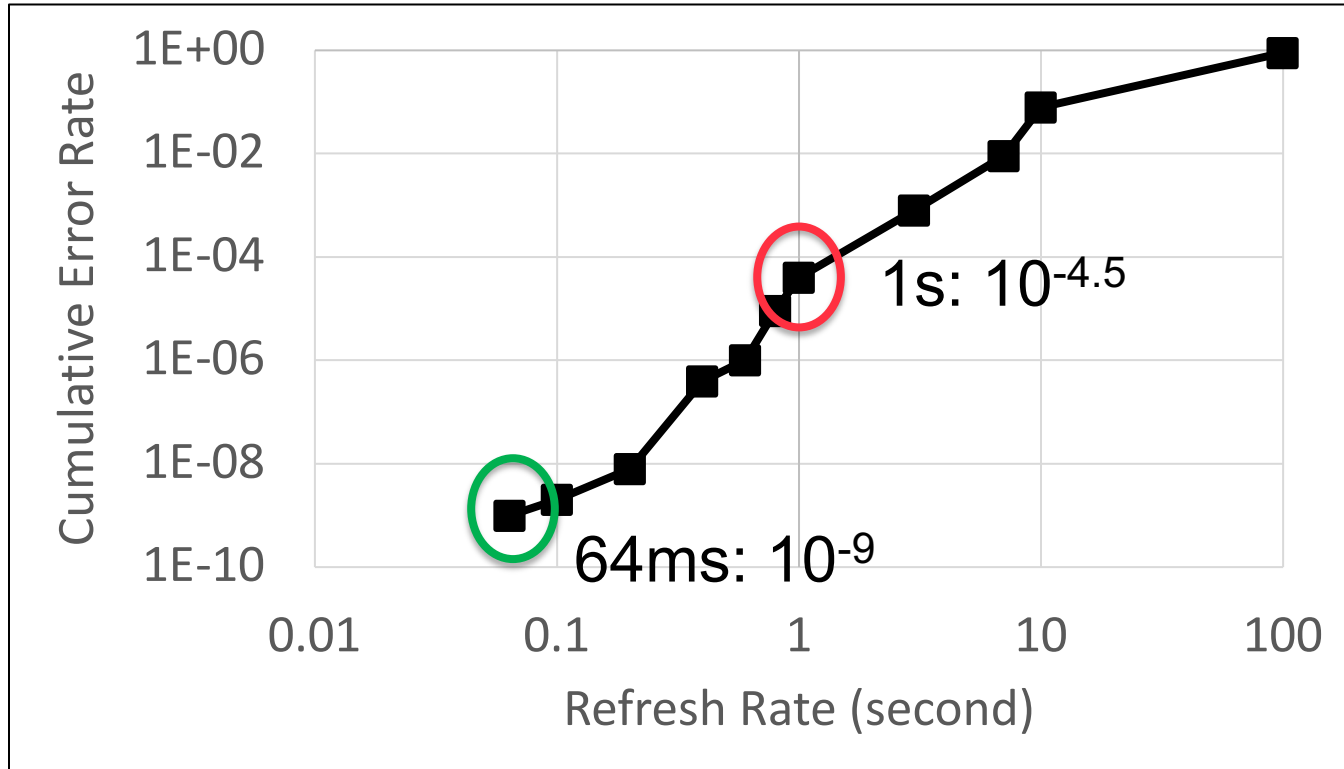
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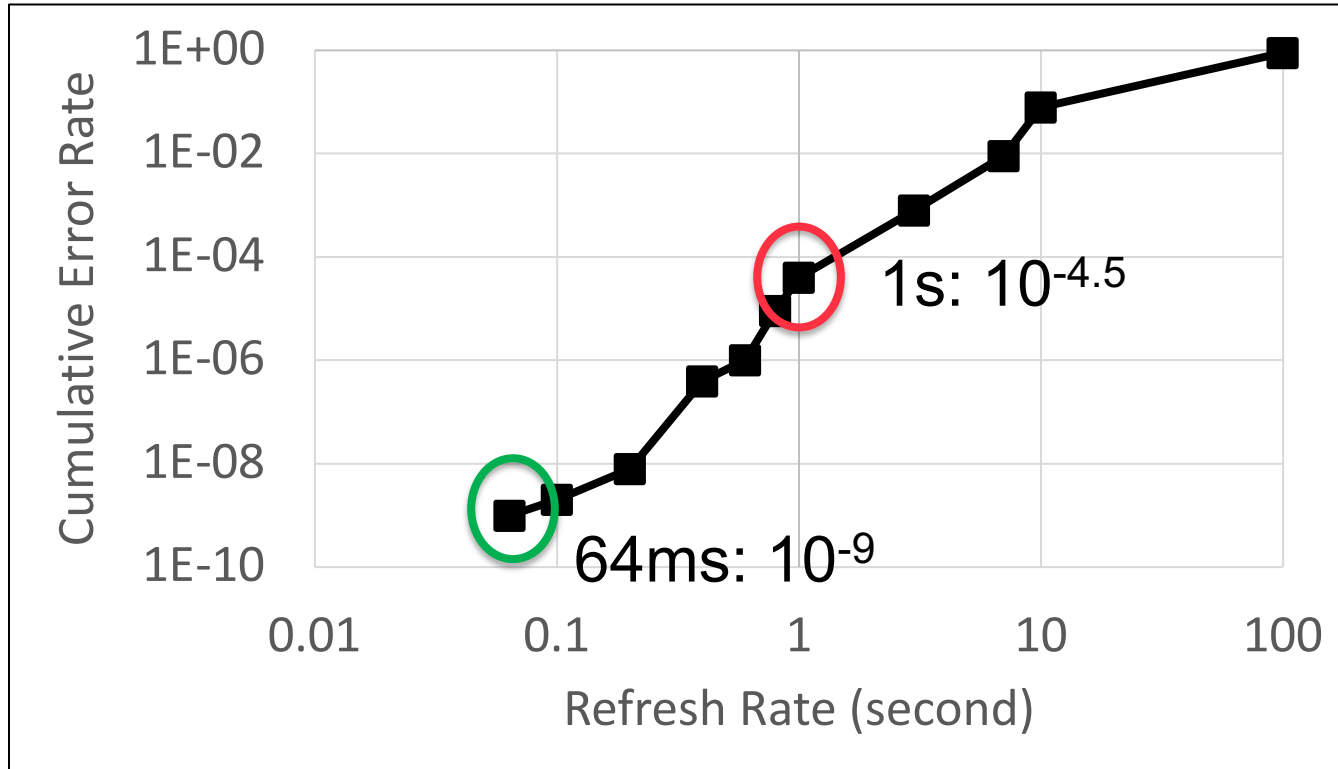
DRAM REFRESH RATE AND ERRORS

DRAM maintains data integrity by Refresh operations



DRAM REFRESH RATE AND ERRORS

DRAM maintains data integrity by Refresh operations



Lowering refresh rate increases bit error rate

ERROR CORRECTION CODE (ECC)

ECC: tolerate refresh errors

Q: how many errors should the system tolerate?

 Errors

ECC Strength

64B cache line

ECC-1



ECC-6





ERROR CORRECTION CODE (ECC)

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 Errors

ECC Strength	64B cache line	Capability
ECC-1		1 Error
ECC-6		6 Errors

ERROR CORRECTION CODE (ECC)

ECC: tolerate refresh errors

Q: how many errors should the system tolerate?

→ **What should be the strength of the ECC?**

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→ **What should be the strength of the ECC?**

ECC Strength	Line Failure	System Failure
ECC-1	1.8×10^{-2}	1.0
ECC-2	9.8×10^{-7}	1.0
ECC-4	1.6×10^{-11}	2.7×10^{-4}
ECC-5	4.9×10^{-14}	8.1×10^{-7}
ECC-6	1.2×10^{-16}	1.8×10^{-9}

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Good

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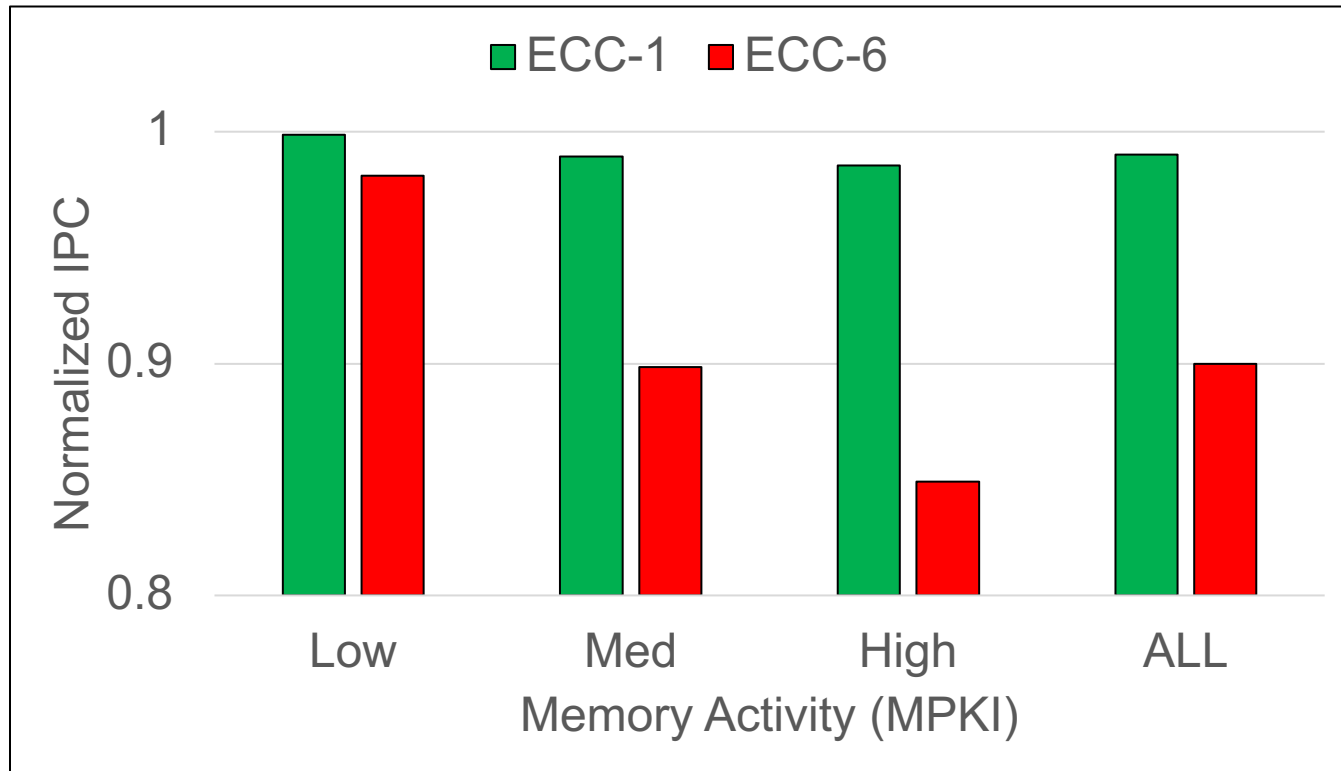


Good

Refresh rate of 1s needs ECC-6 for errors

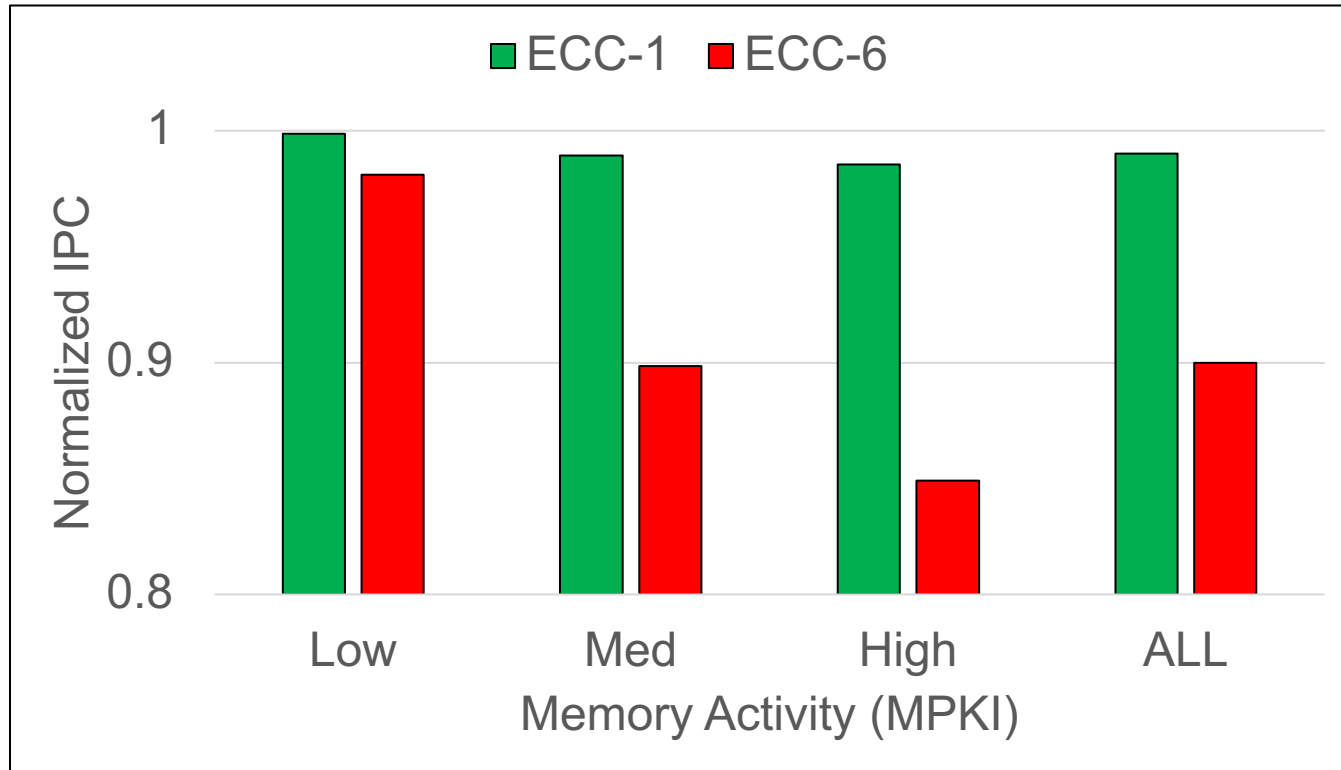
DRAWBACKS OF ECC-6

Single Core, 1MB Cache, 1GB DRAM



DRAWBACKS OF ECC-6

Single Core, 1MB Cache, 1GB DRAM





ECC-6 incurs huge performance degradation





WHAT IS THE IDEAL CASE?

	Goal
Active Mode	Performance (Refresh Power Negligible)
Idle Mode	Energy (Performance Not Critical)





WHAT IS THE IDEAL CASE?

	Goal	Strong ECC
Active Mode	Performance (Refresh Power Negligible)	 Bad
Idle Mode	Energy (Performance Not Critical)	 Good

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	Goal	Strong ECC	Weak ECC
Active Mode	Performance (Refresh Power Negligible)	 Bad	 Good
Idle Mode	Energy (Performance Not Critical)	 Good	 Bad

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Ideally, we want ECC-1 in active mode, and ECC-6 in idle mode

WHAT IS THE IDEAL CASE?

	Goal	Strong ECC	Weak ECC
Active Mode	Performance (Refresh Power Negligible)	?	✓ Good
Idle Mode	Energy (Performance Not Critical)	✓ Good	?

Ideally, we want ECC-1 in active mode, and ECC-6 in idle mode

AGENDA

- Introduction
- Background
- **Morphable ECC (MECC)**
 - Overview
 - Design
 - ECC Support and Storage
- Results
- Summary

MECC: OVERVIEW

Active

Time



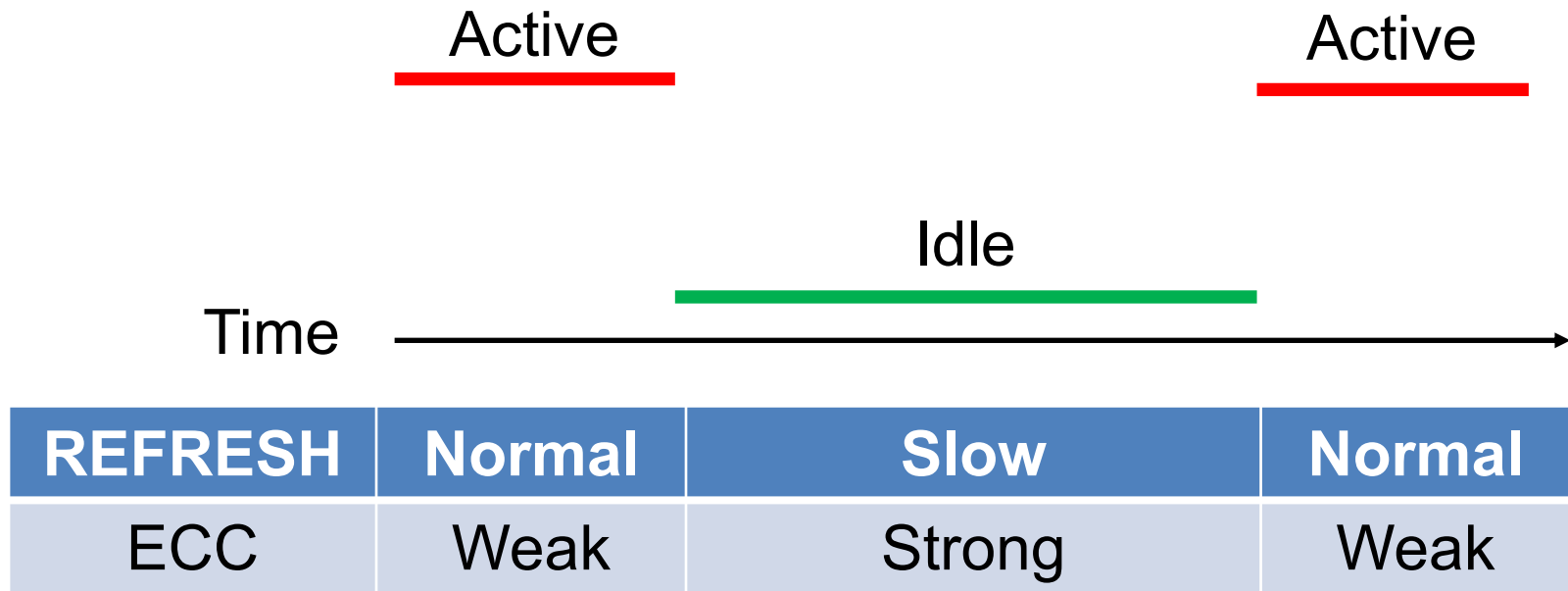
REFRESH

Normal

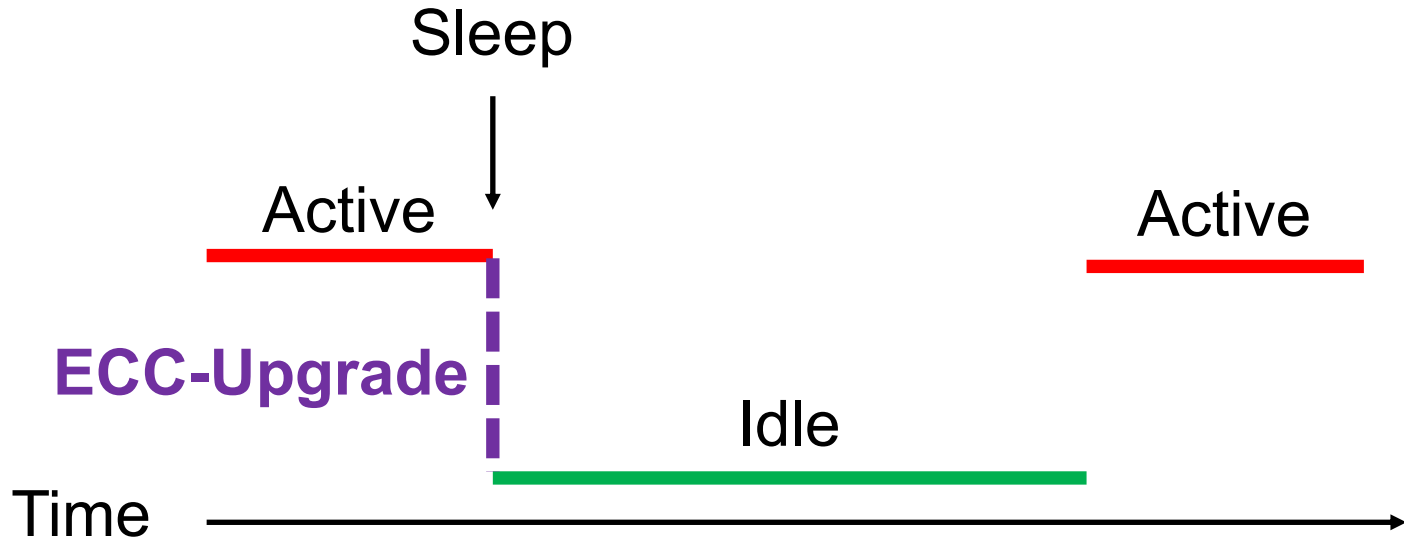
ECC

Weak

MECC: OVERVIEW



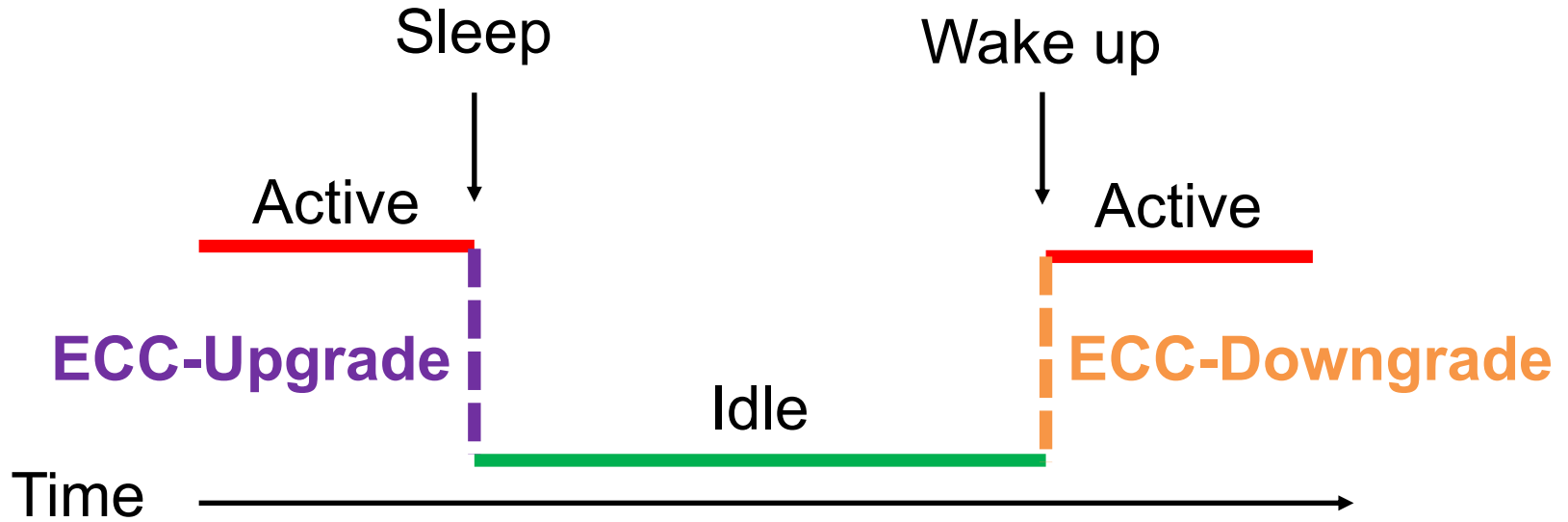
MECC: OVERVIEW



REFRESH	Normal	Slow	Normal
ECC	Weak	Strong	Weak

ECC-Upgrade

MECC: OVERVIEW

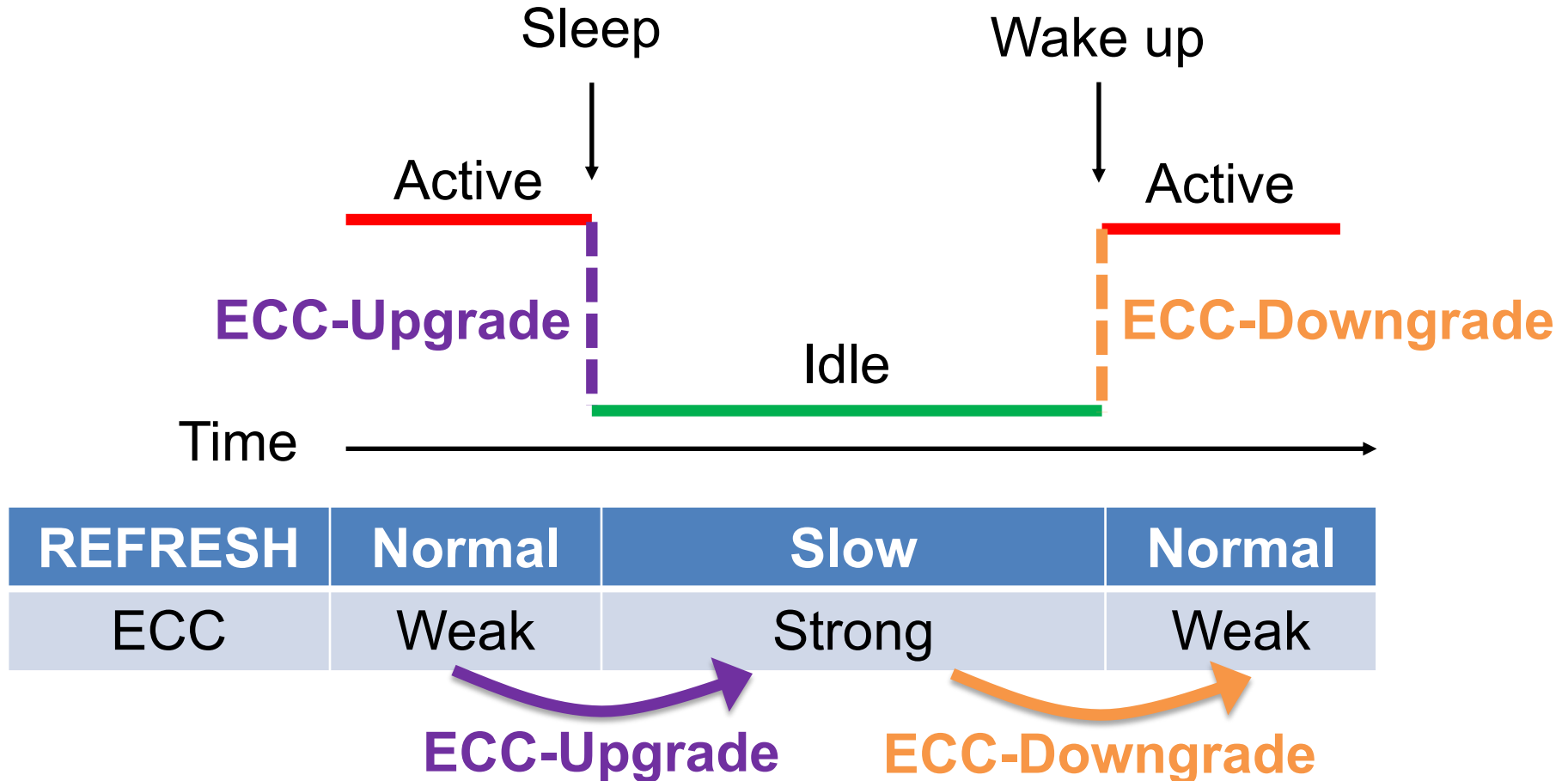


REFRESH	Normal	Slow	Normal
ECC	Weak	Strong	Weak

ECC-Upgrade (purple arrow from Weak to Strong)

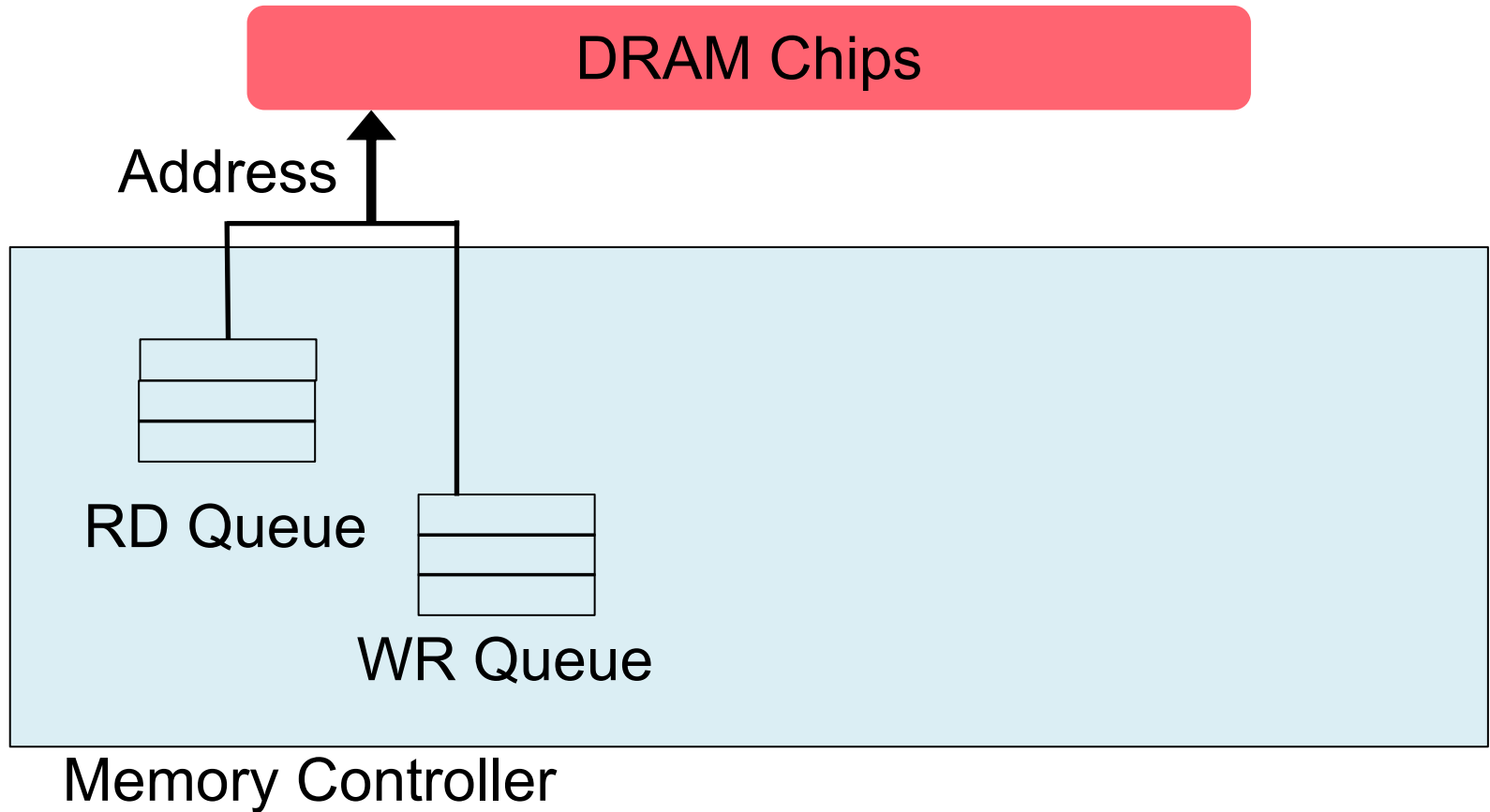
ECC-Downgrade (orange arrow from Strong to Weak)

MECC: OVERVIEW

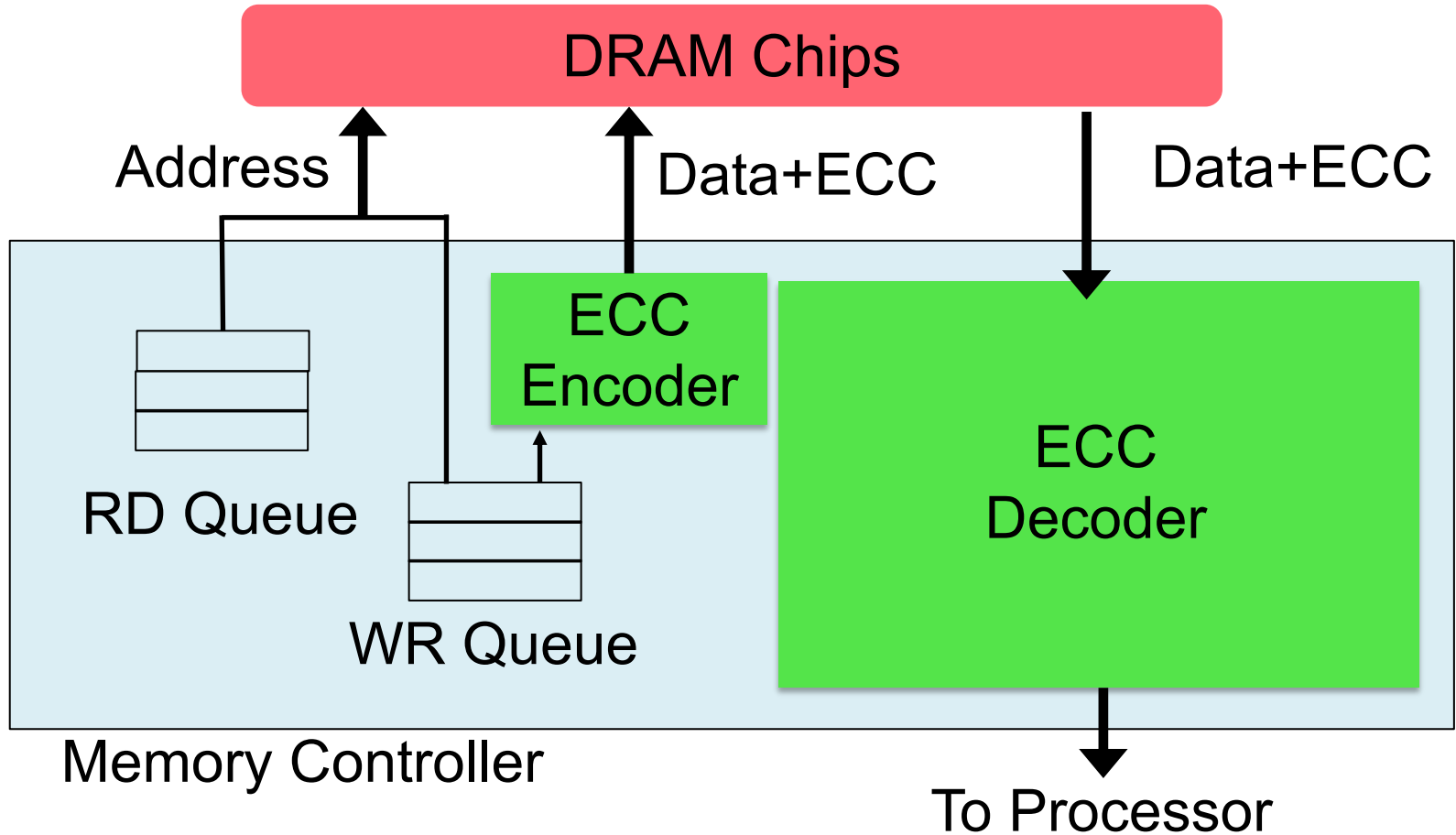


MECC uses two ECCs based on modes

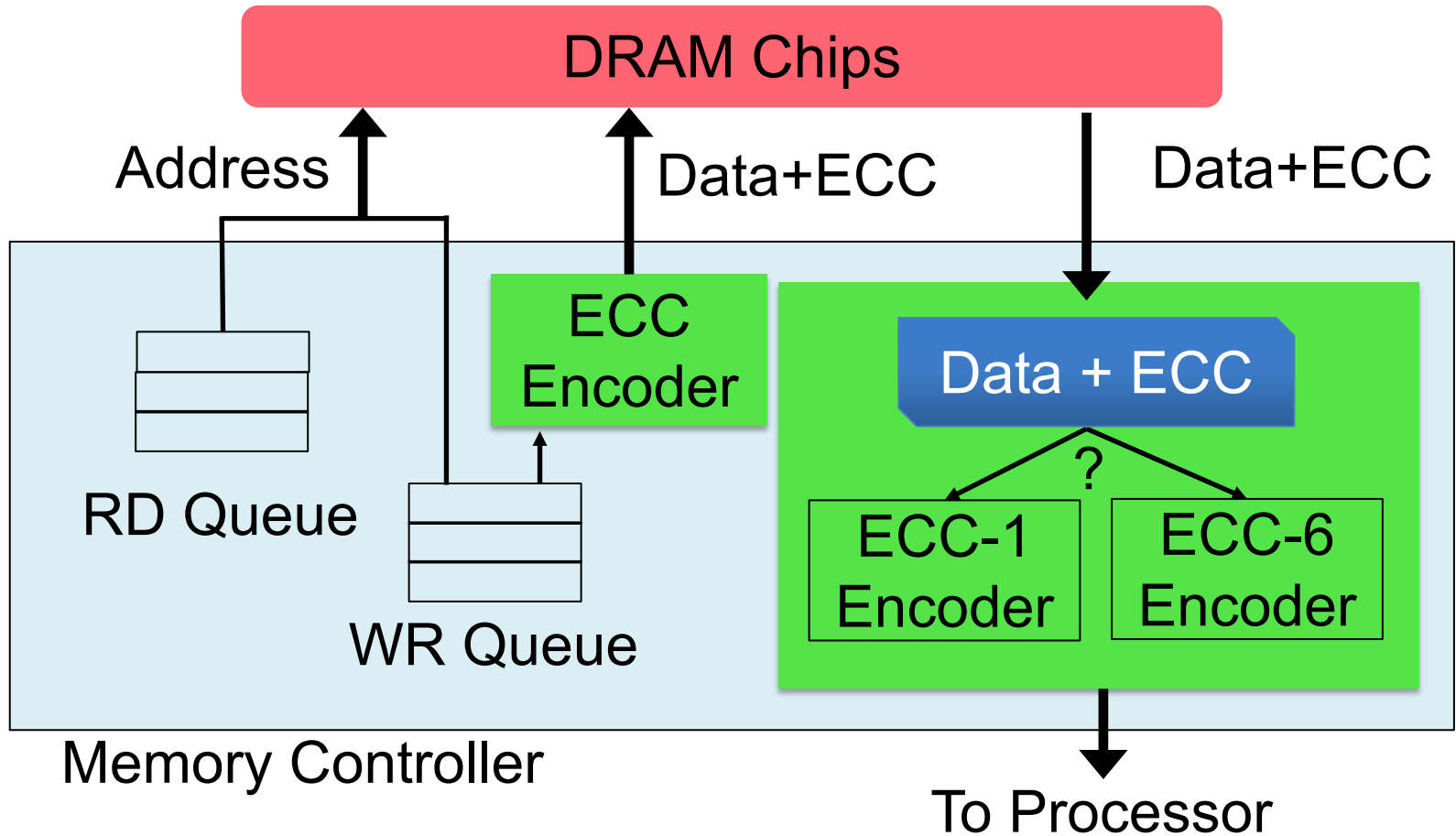
MECC: DESIGN



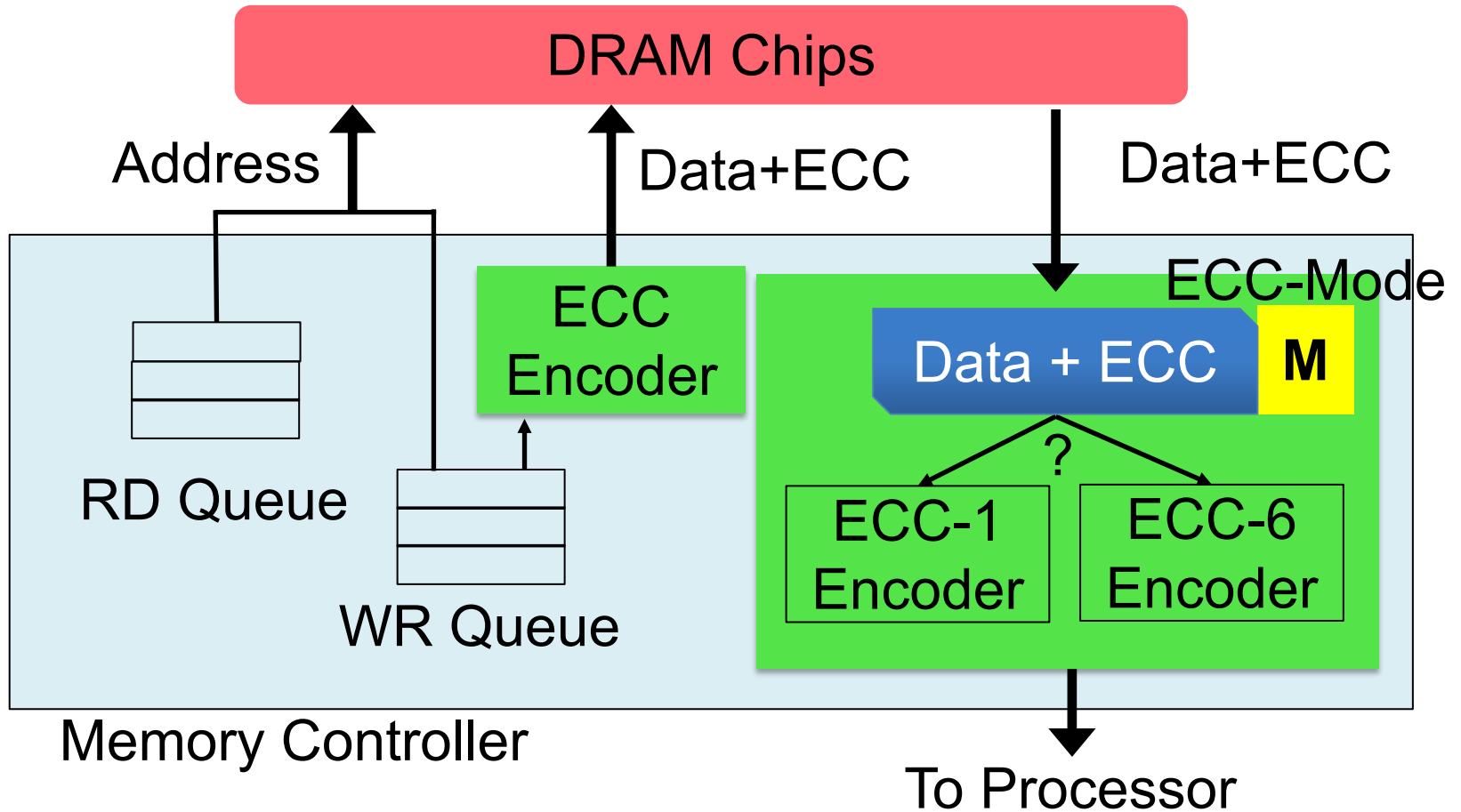
MECC: DESIGN



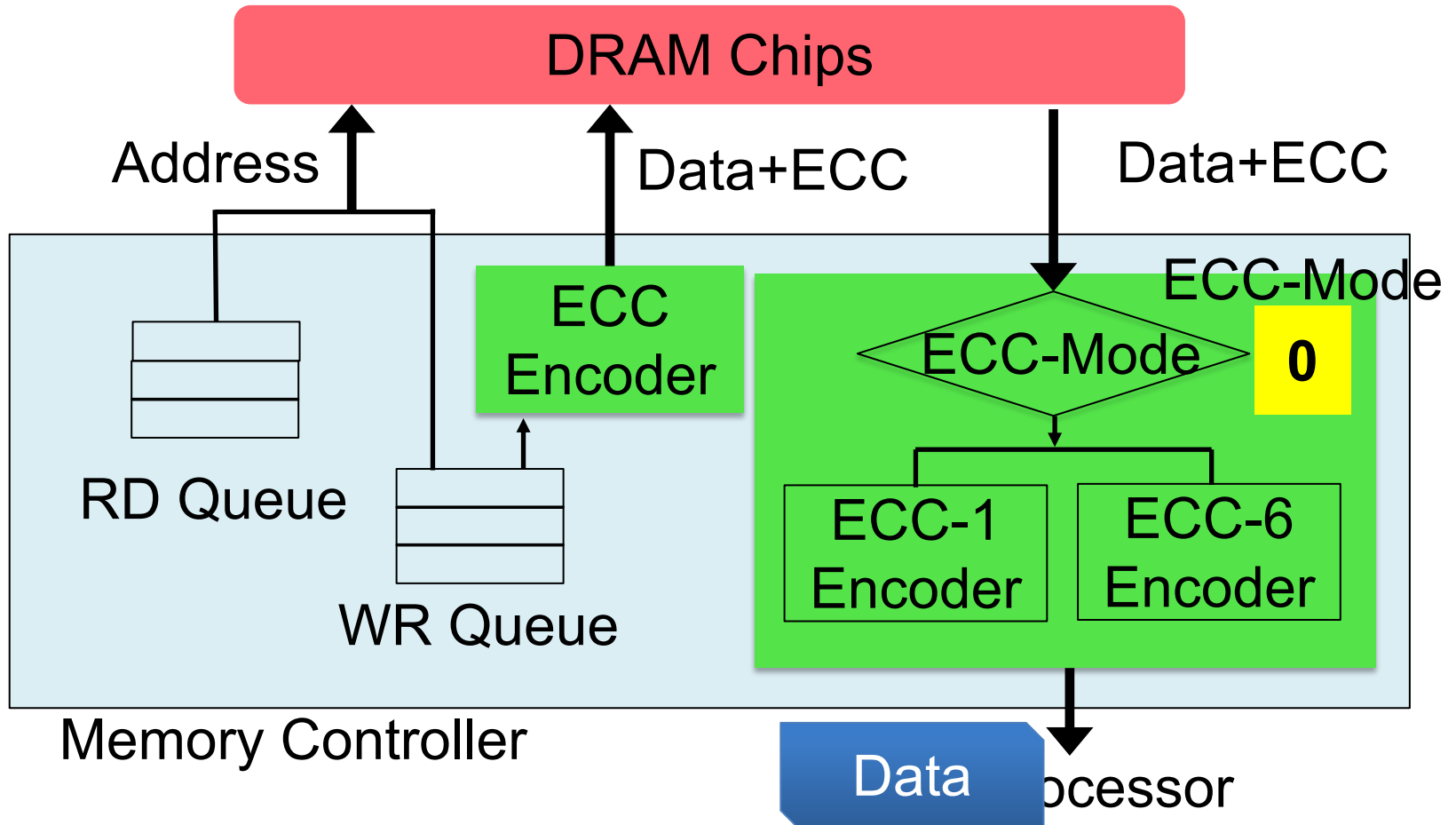
MECC: DESIGN



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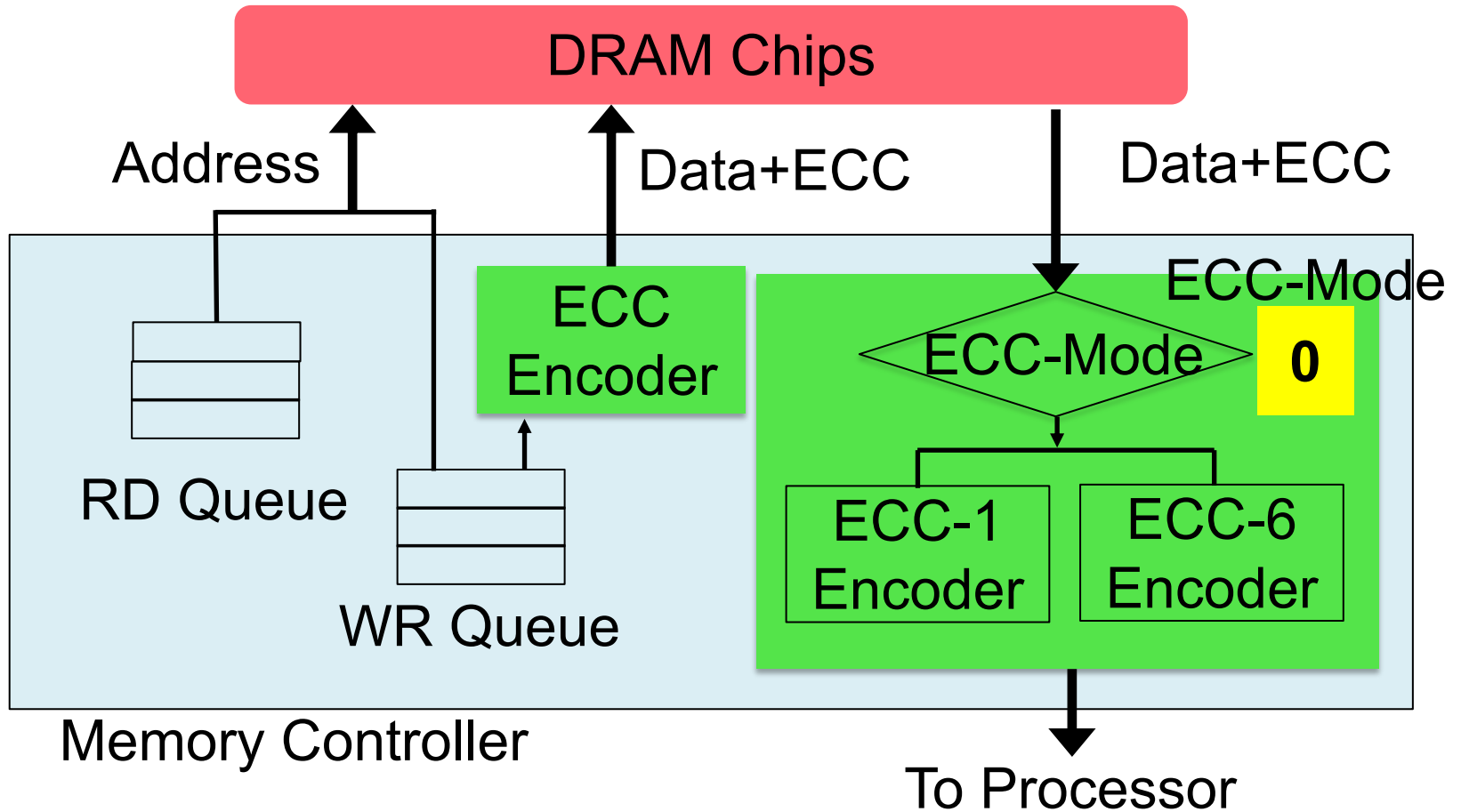


MECC: DESIGN



Memory controller uses ECC-mode bits to decode with different ECCs

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Memory controller uses ECC-mode bits to decode with different ECCs

MECC: ECC STORAGE

64B Data Block

8B ECC



MECC: ECC STORAGE

64B Data Block

8B ECC



MECC ECC-1 11 bits

MECC ECC-6 60 bits

MECC: ECC STORAGE

64B Data Block

8B ECC



MECC ECC-1

11 bits

+

MECC ECC-6

60 bits

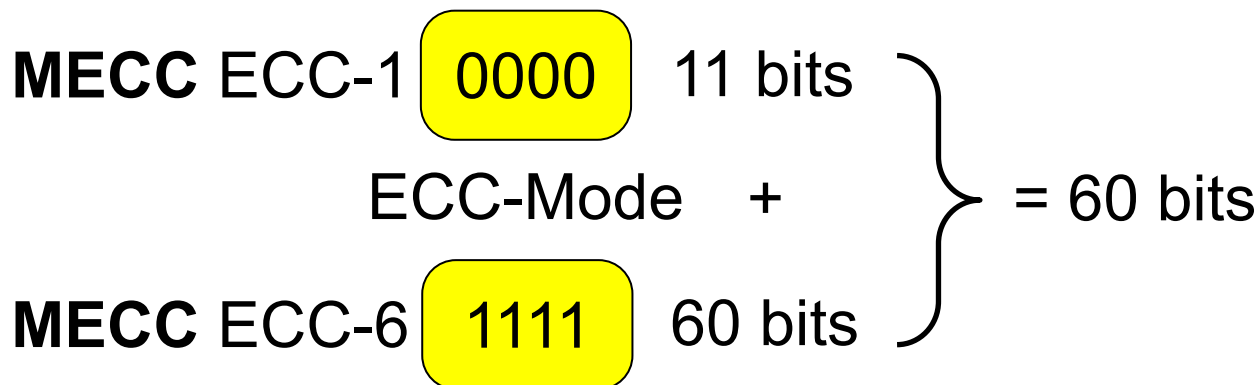
} = 60 bits



MECC: ECC STORAGE

64B Data Block

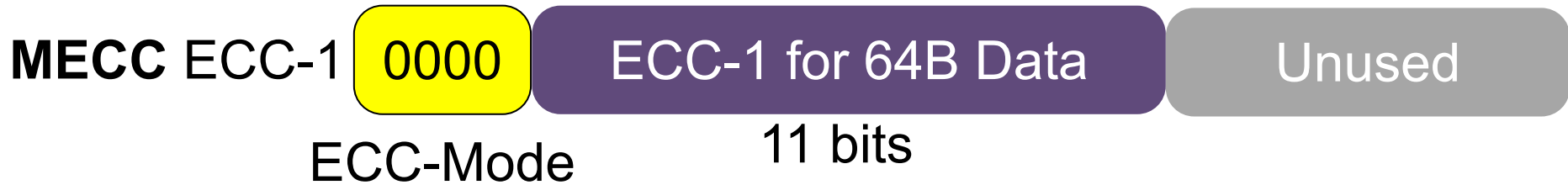
8B ECC



MECC: ECC STORAGE

64B Data Block

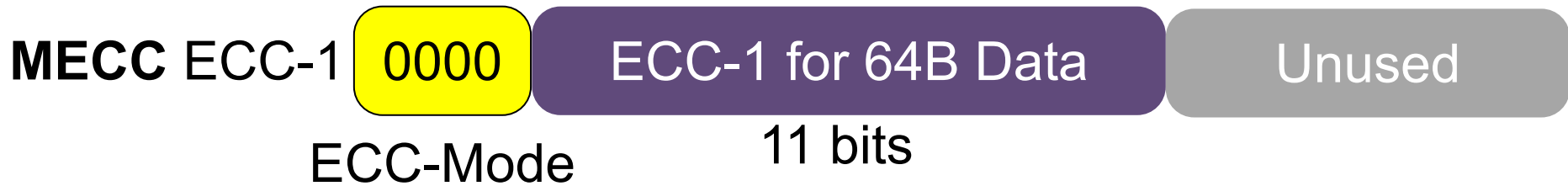
8B ECC



MECC: ECC STORAGE

64B Data Block

8B ECC

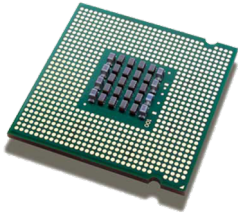


MECC uses existing space to store 2 ECCs

AGENDA

- Introduction
- Background
- Morphable ECC
- **Results**
- Summary

METHODOLOGY



CPU



Off-chip DRAM

Core Chips:

- 1 cores 1.6 GHz
- 2-wide In-Order
- 1MB cache

LPDDR2

Capacity

1GB

Bus

DDR 200MHz

Organization

1 channels,
4 banks

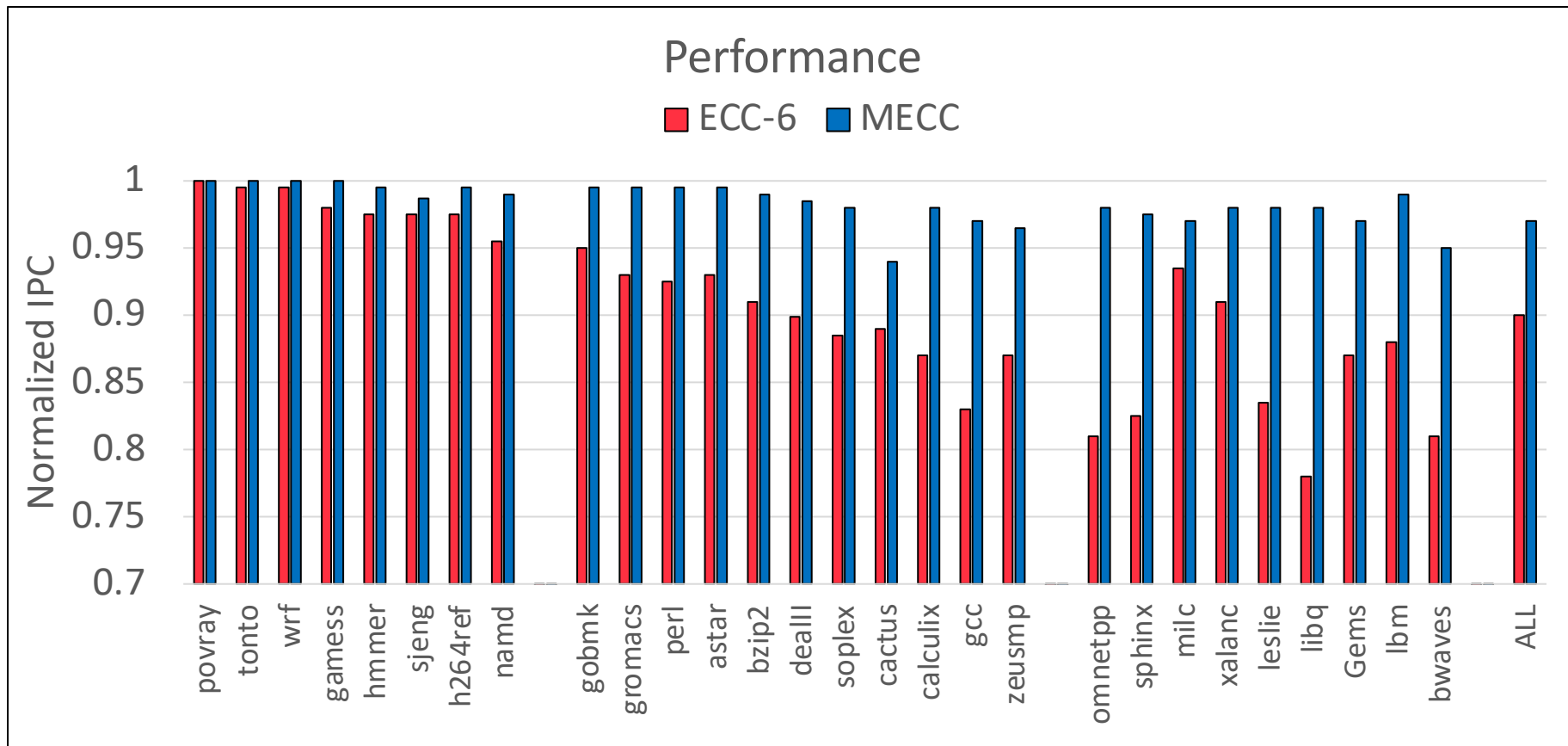
- USIMM for DRAM model and power
- Baseline: No Error Correction Code
- SPEC2006 (exclude mcf): low, medium, high MPKI workloads

POWER AND ENERGY CONSUMPTION

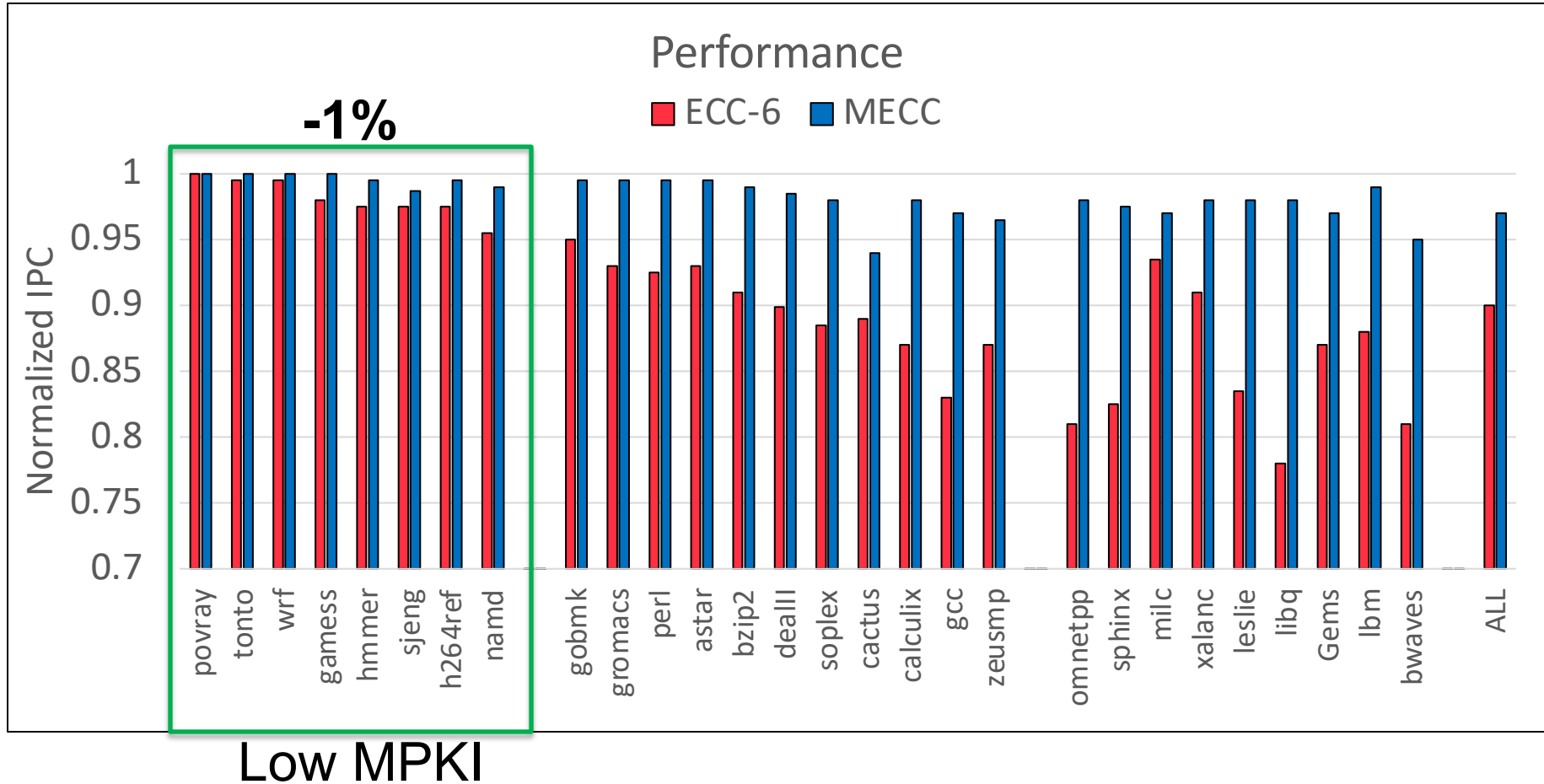
Parameters	Values	Description
VDD	1.7 V	Operating Voltage
IDD0	95 mA	1 bank active precharge current
IDD2P	0.6 mA	Precharge power-down standby current
IDD3P	3 mA	Active power-down standby current
IDD4	135 mA	Burst read/write: 1 bank active
IDD5	100 mA	Auto refresh
IDD8	1.3 mA	Self refresh

$$\text{Power in Idle Mode} = (P_{\text{refresh original}} * T_{\text{original}} / T_{\text{MECC}}) + P_{\text{other}}$$

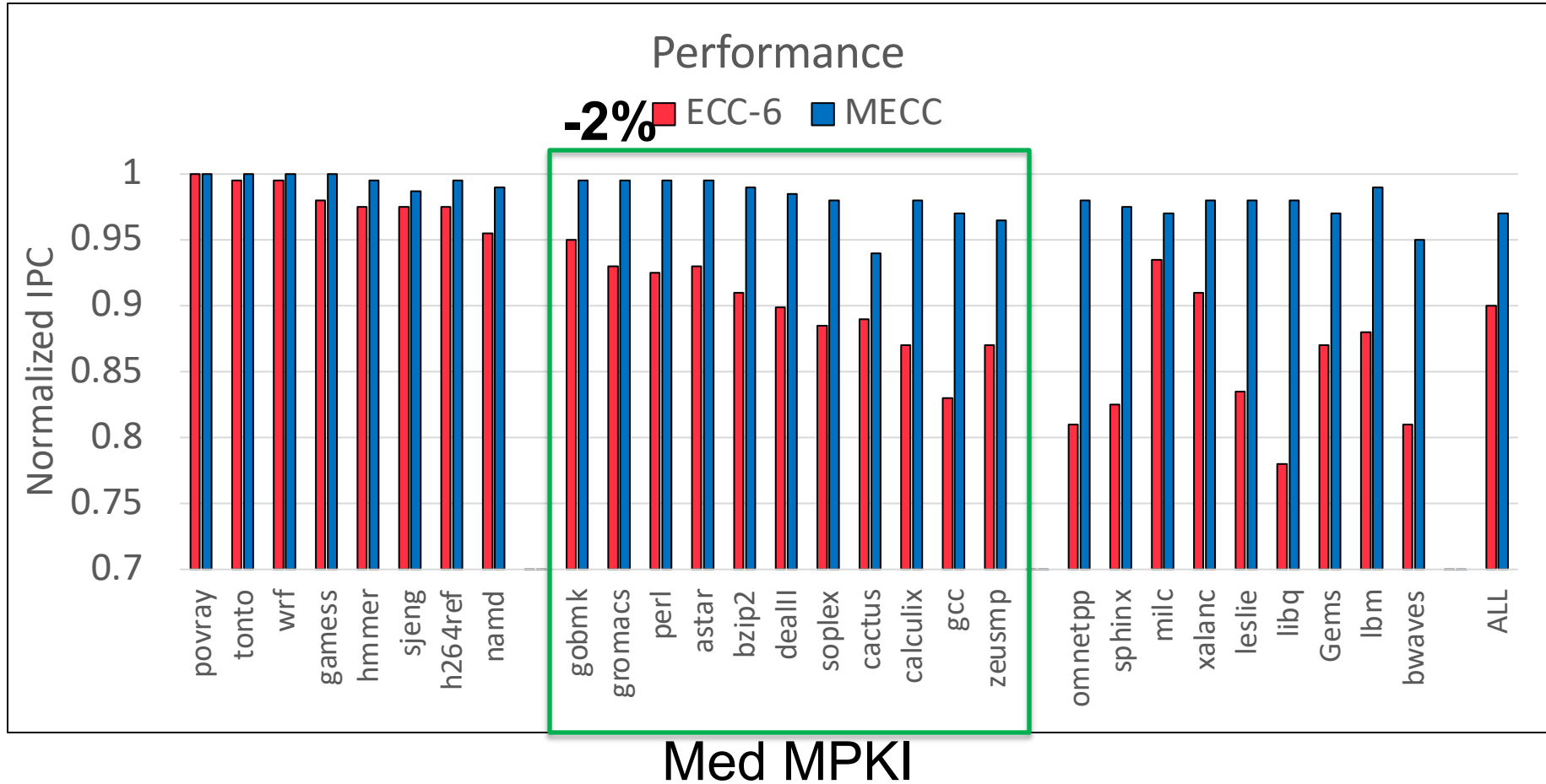
PERFORMANCE IN ACTIVE MODE



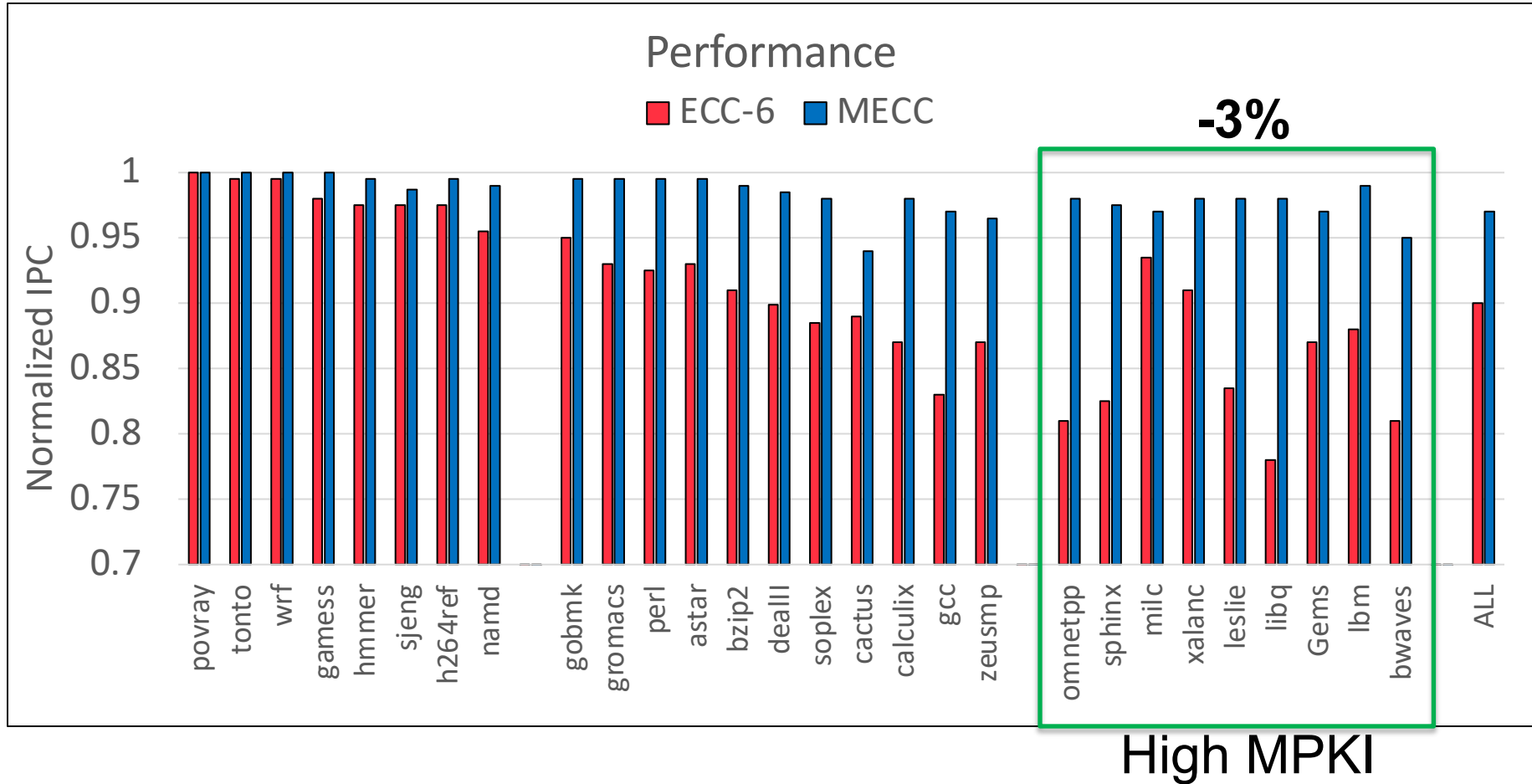
PERFORMANCE IN ACTIVE MODE



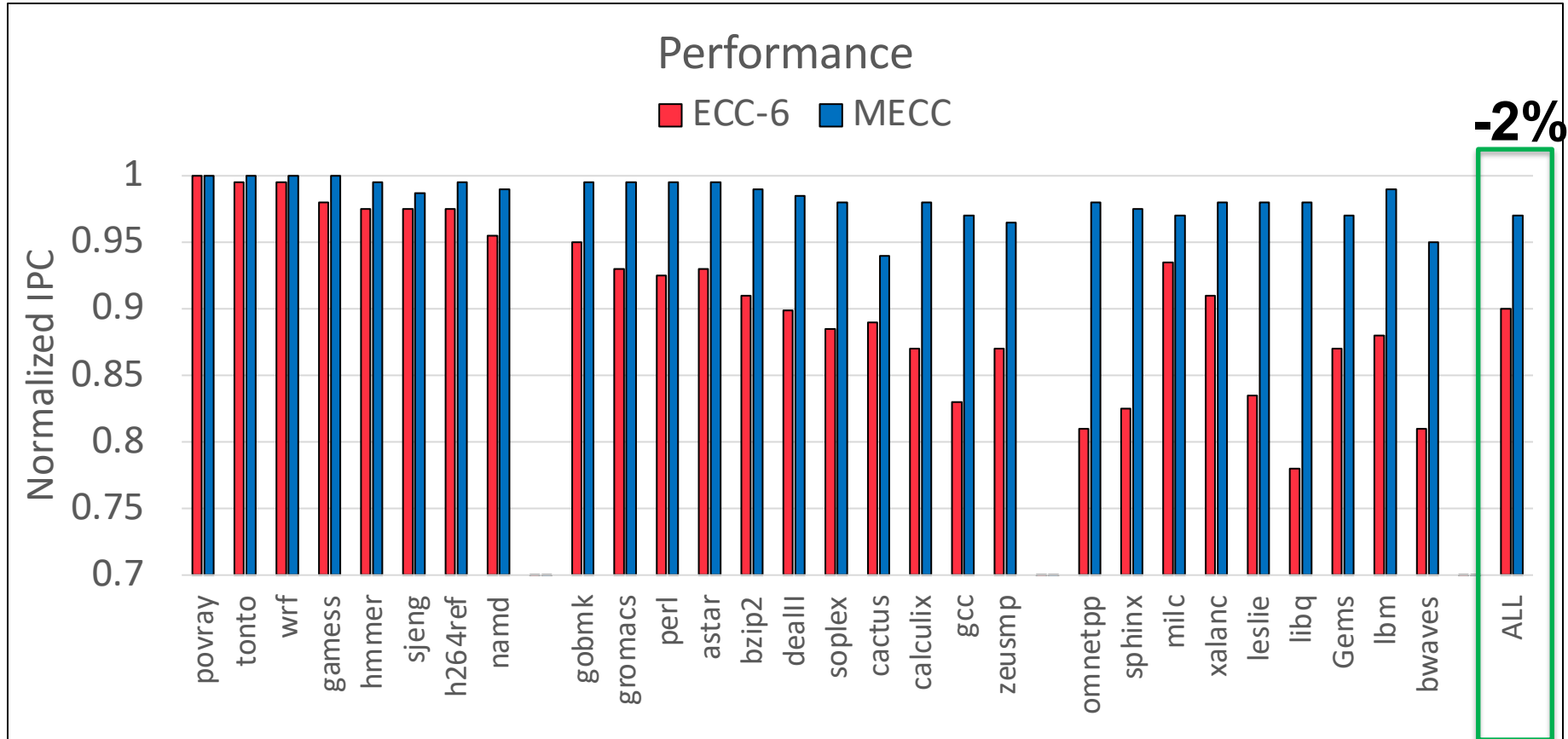
PERFORMANCE IN ACTIVE MODE



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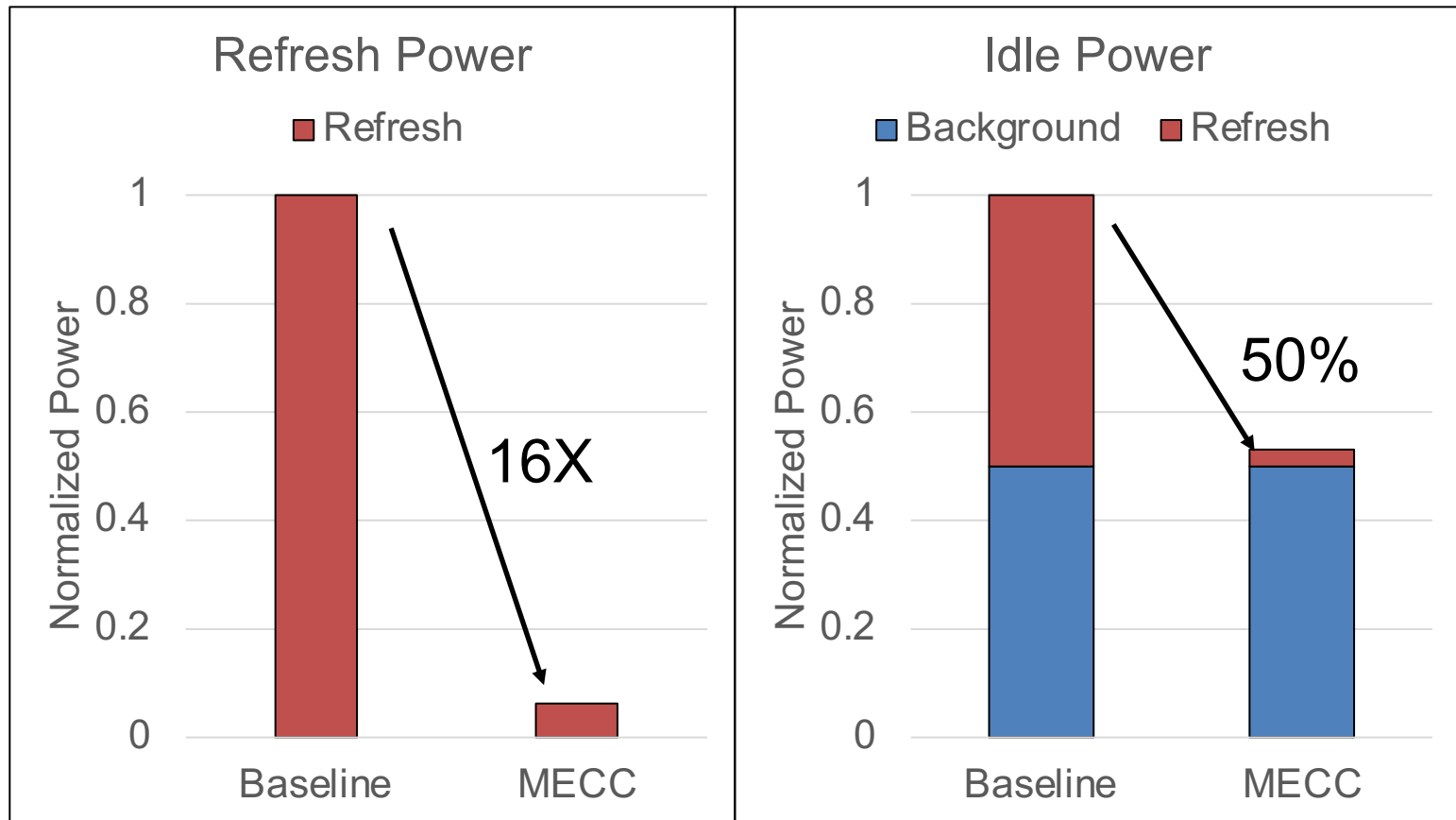


PERFORMANCE IN ACTIVE MODE



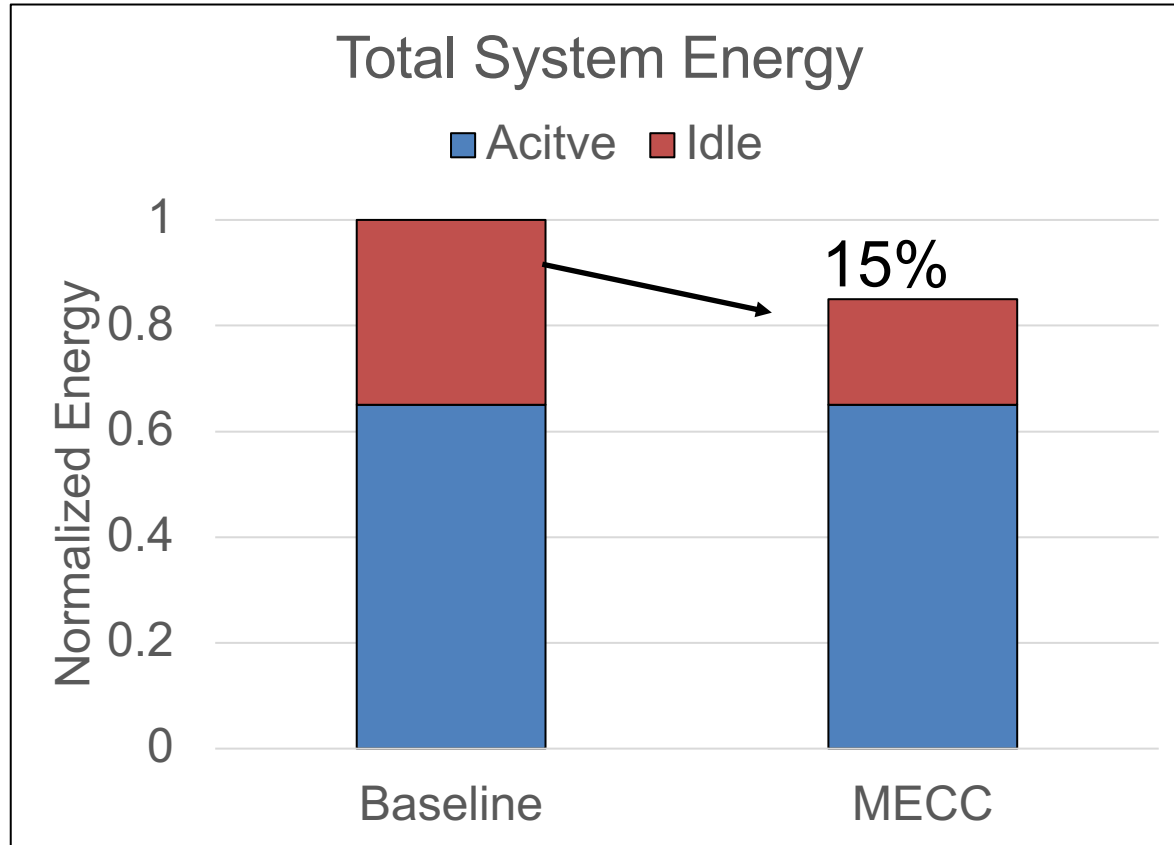
MECC limits the degradation within 2%

POWER SAVING IN IDLE MODE



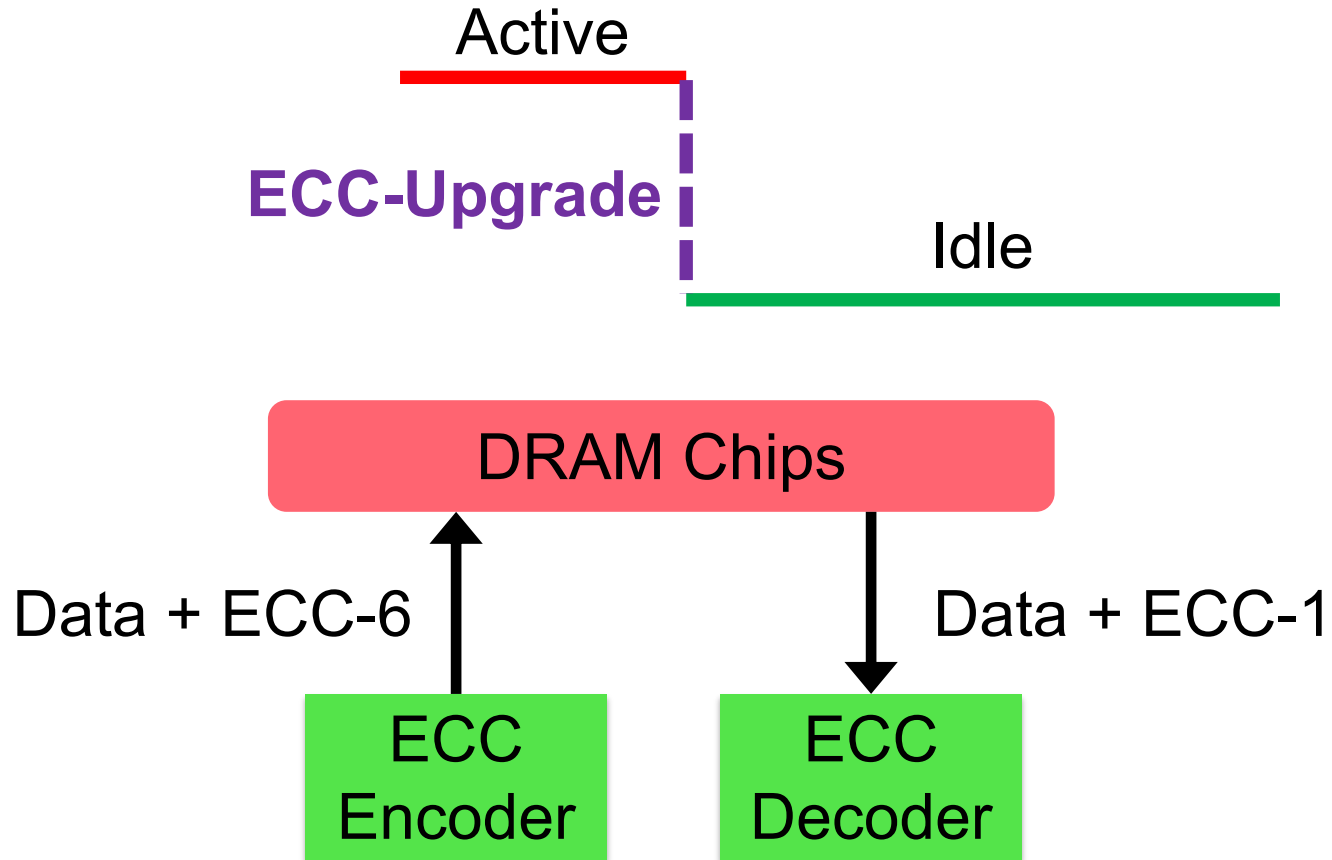
MECC saves idle power by 50%

TOTAL ENERGY SAVINGS

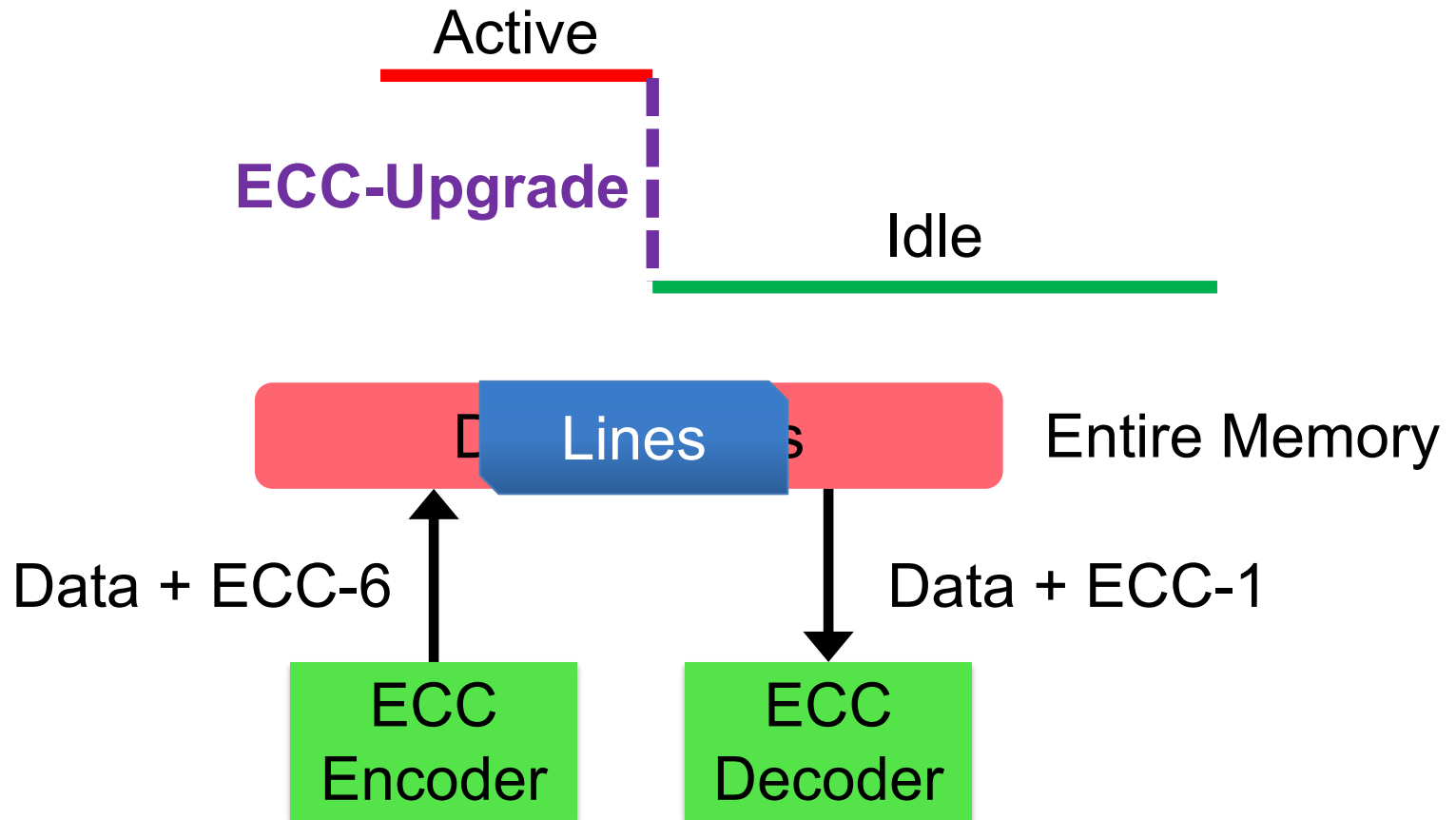


MECC saves total energy by 15%

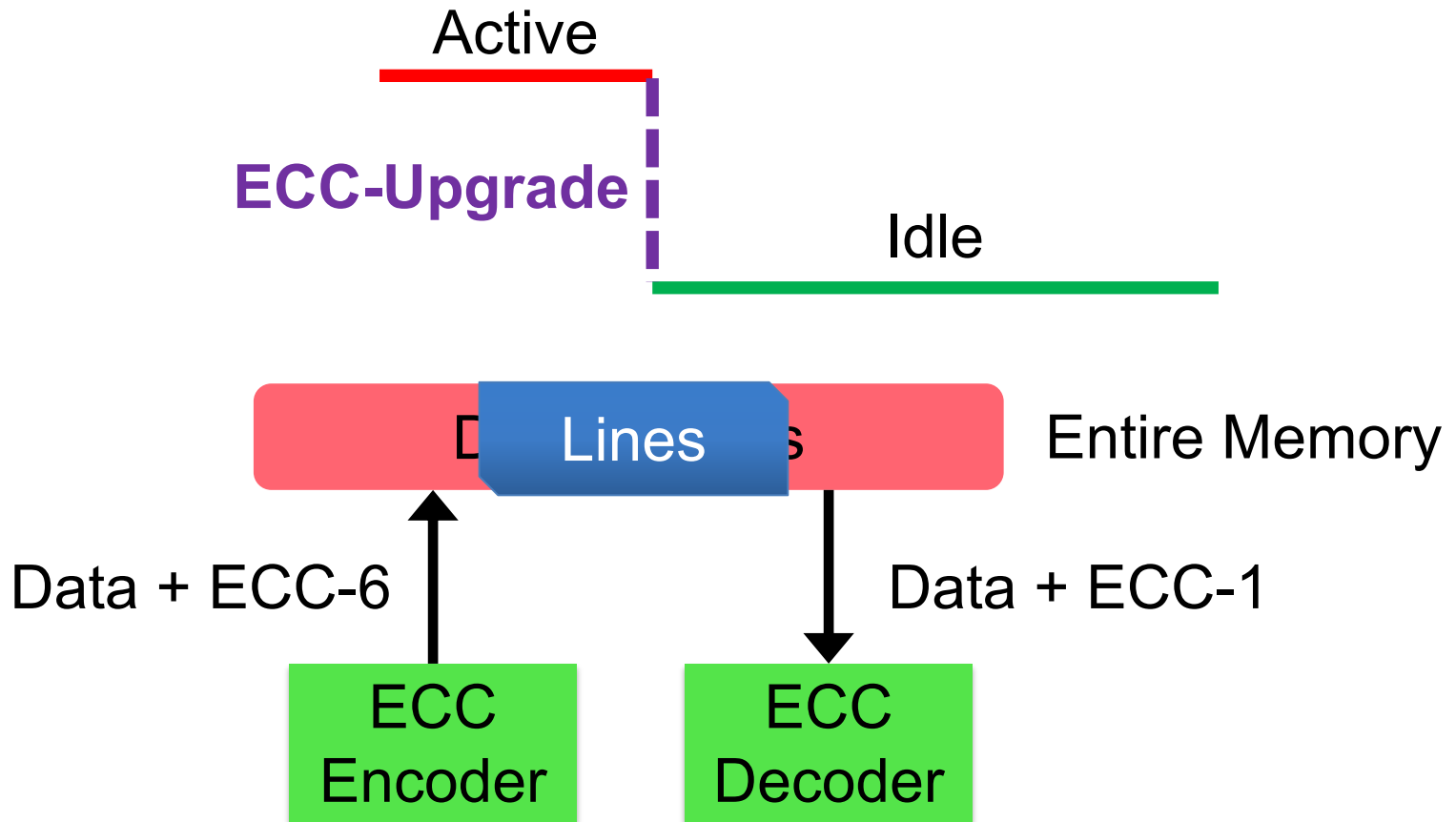
ECC-UPGRADE



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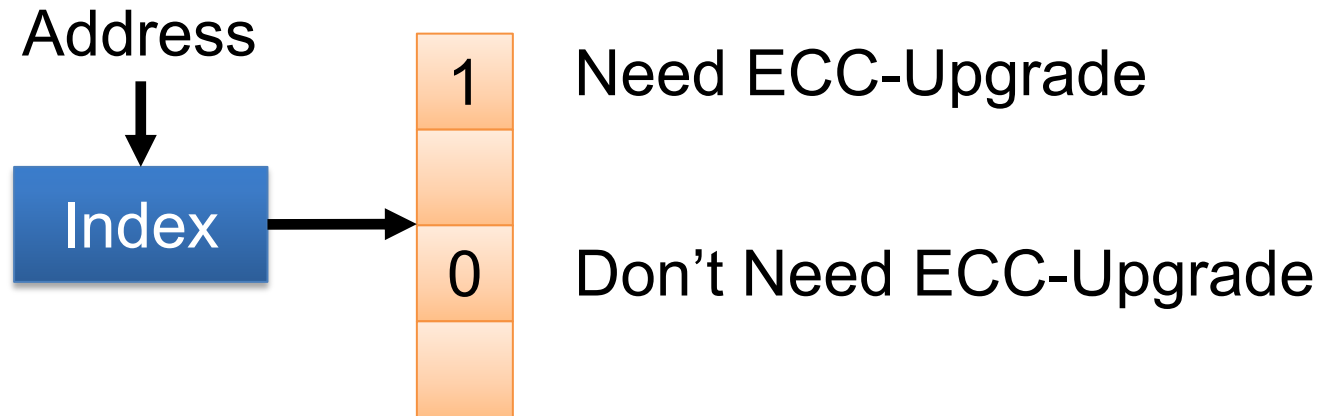


ECC-UPGRADE

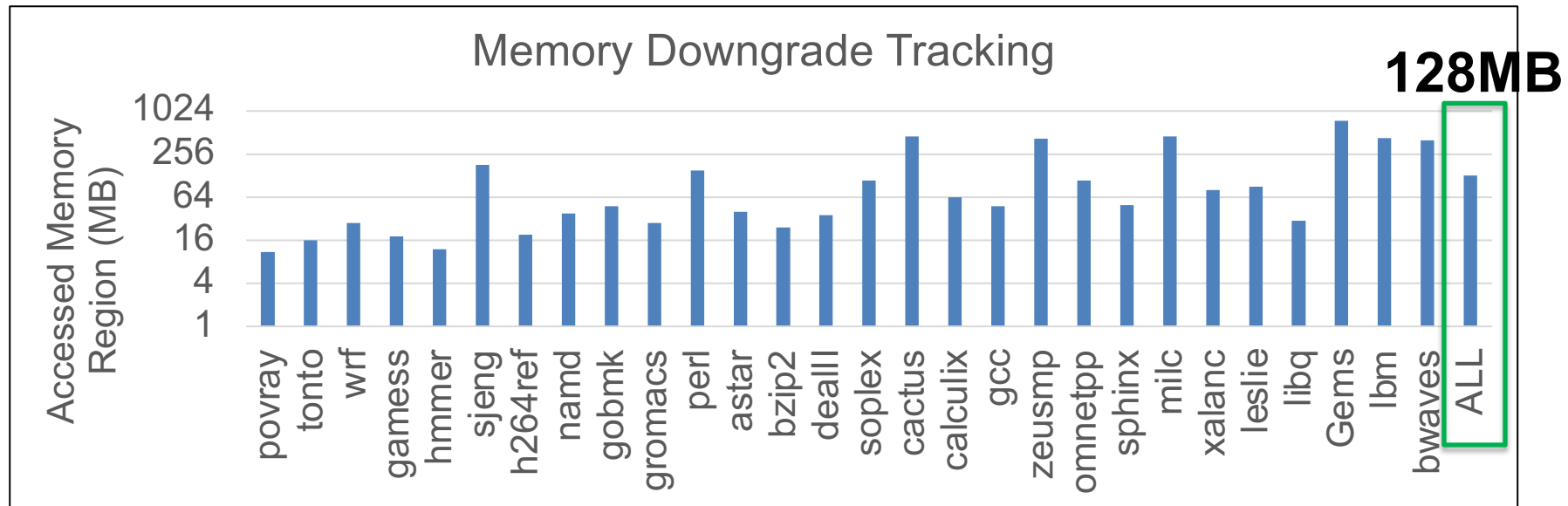
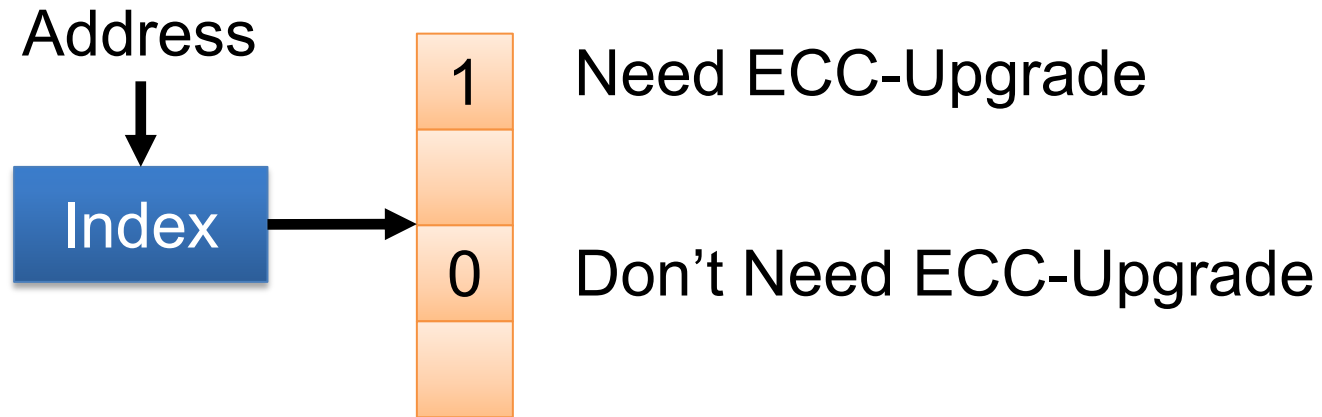


Can we enhance the ECC-Upgrade?

MEMORY DOWNGRADE TRACKING (MDT)



MEMORY DOWNGRADE TRACKING (MDT)



MDT avoids unnecessary ECC-Upgrades

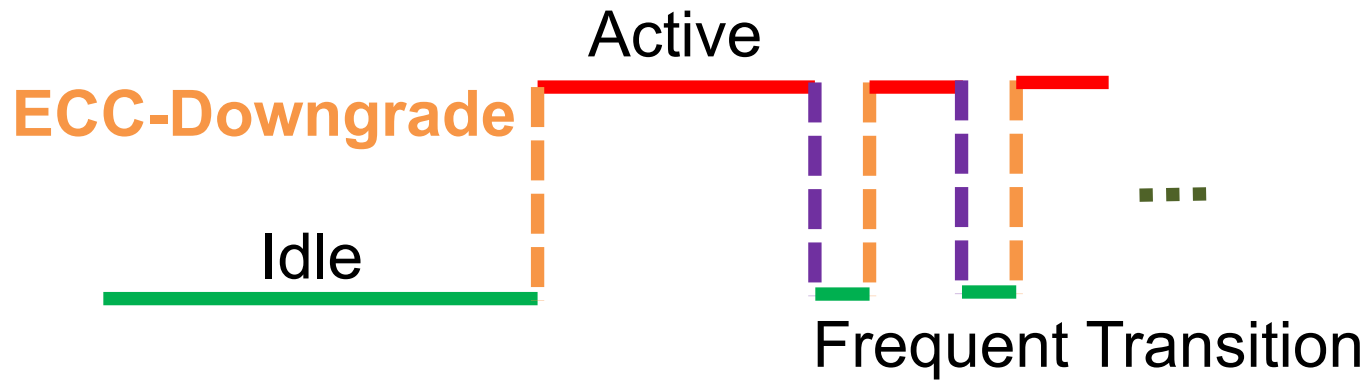
FREQUENT TRANSITION OF ECC STATES



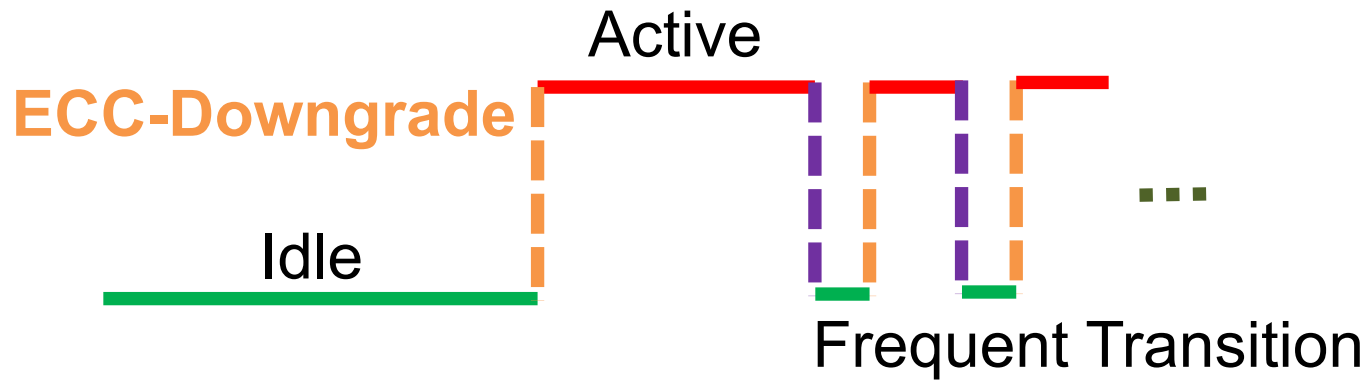
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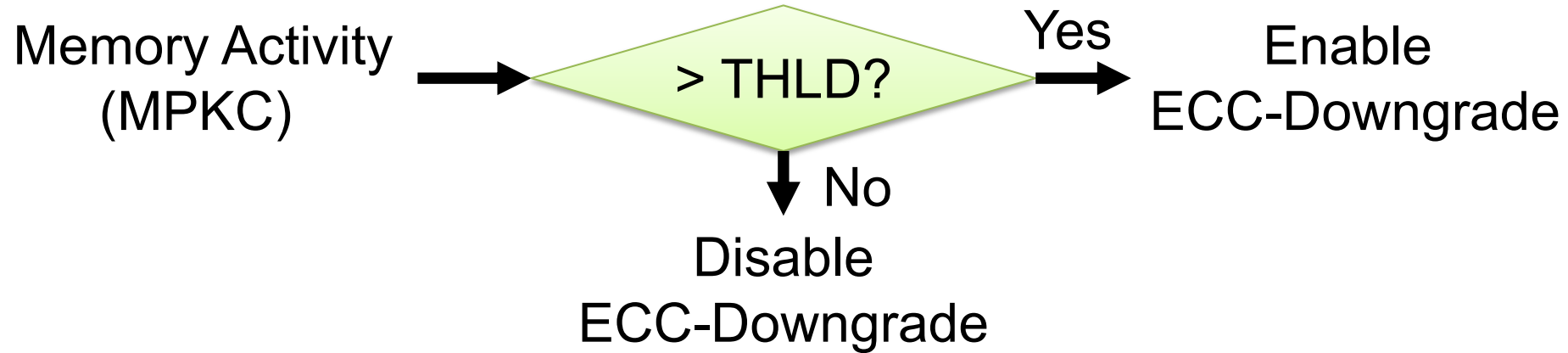


FREQUENT TRANSITION OF ECC STATES

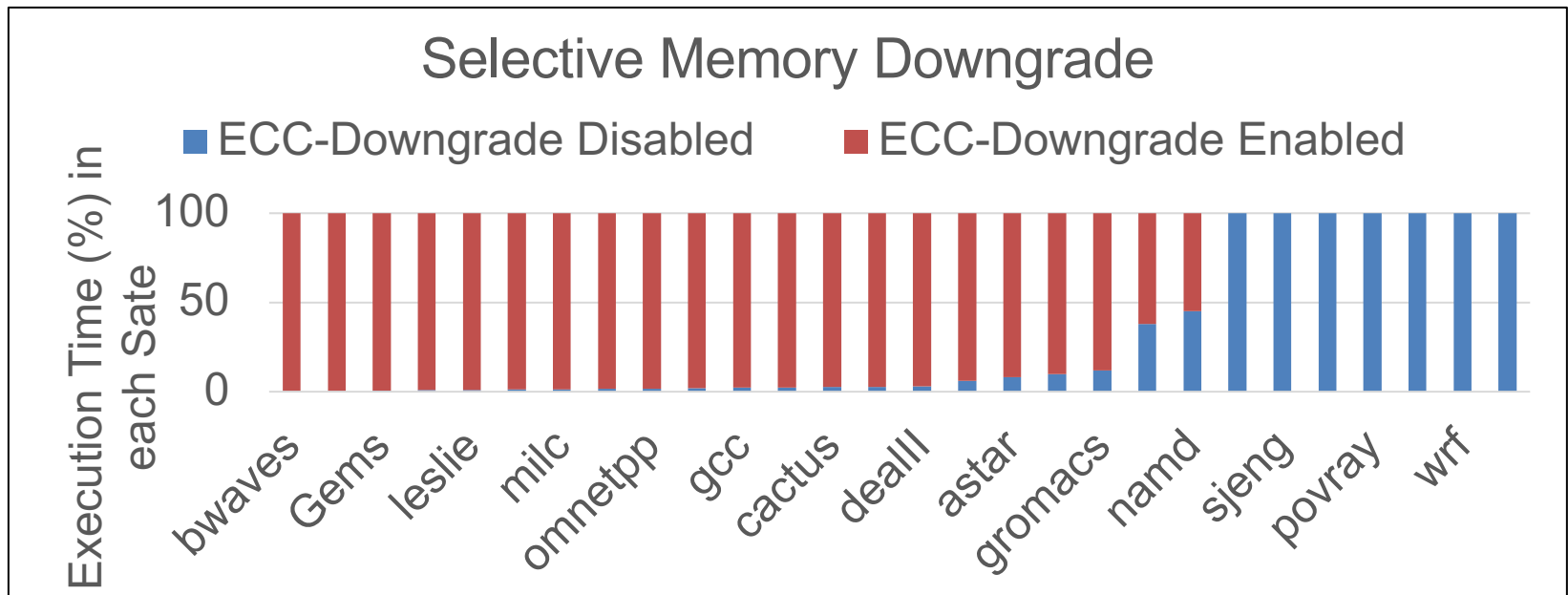
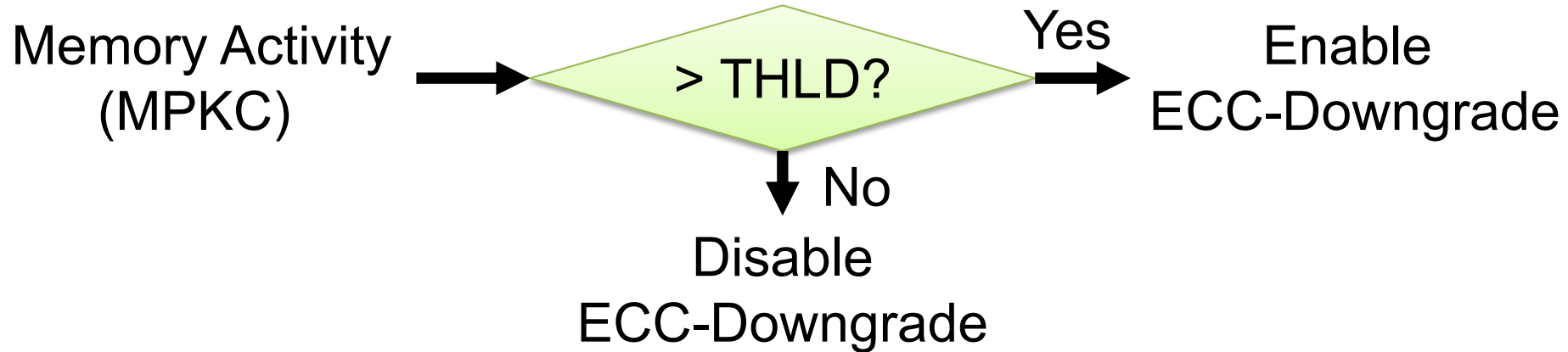


Can we enhance the ECC-Downgrade?

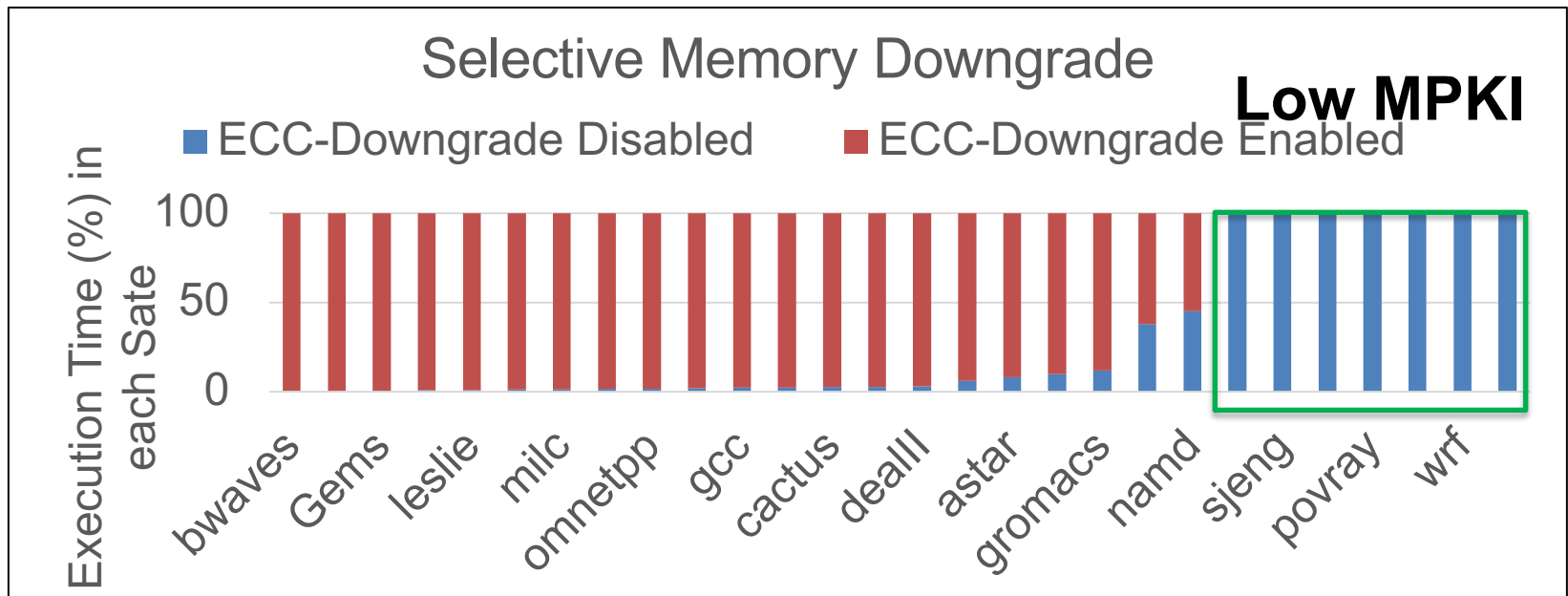
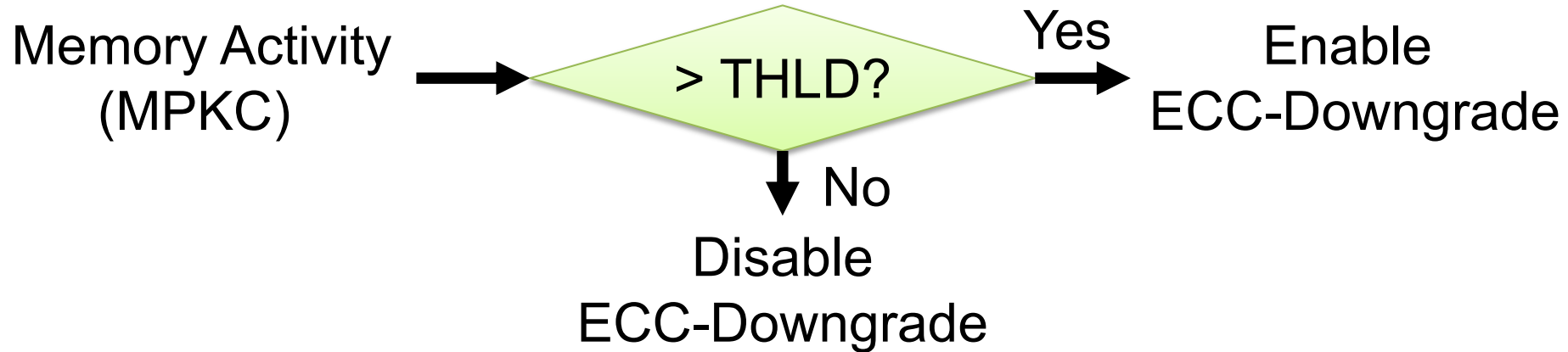
SELECTIVE MEMORY DOWNGRADE (SMD)



SELECTIVE MEMORY DOWNGRADE (SMD)



SELECTIVE MEMORY DOWNGRADE (SMD)



SMD avoids frequent transition of ECCs

EXECUTIVE SUMMARY

- Energy consumption determines the usability of emerging mobile computing devices
- DRAM refresh operations accounts for significant fraction of memory system's energy

	Strong ECC	Weak ECC
Active Mode (refresh power negligible)	Bad Performance	Good Performance
Idle Mode (performance not critical)	Huge Energy Savings	No Energy Saving

- Results: -50% idle power, -15% overall energy, with only 2% performance degradation

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